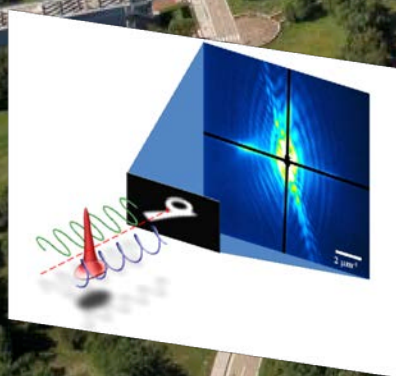
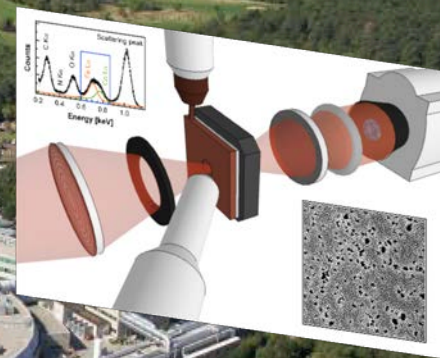


Introduction to X-ray microscopy and spectroscopy

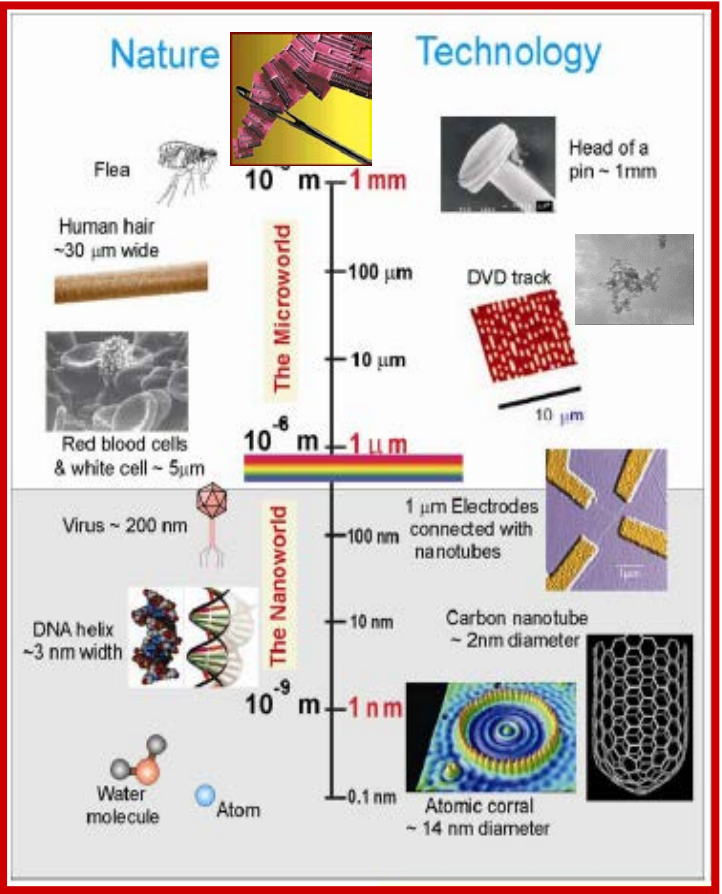




An Invitation to Enter a New Field of Physics & Material Science

Richard P. Feynman - 1959!!!

There's Plenty of Room at the Bottom



'NANO'
By nature, design or externally-induced changes

- Materials have properties varying at various depth and length scales and are usually laterally inhomogeneous at atomic, nano or meso scales.
- Structure and chemical composition usually is different at the surface and in the bulk.
- New properties expected with decreasing the dimensions stepping into nanoworld.

What we NEED:

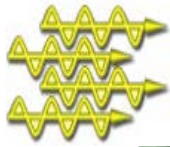
Chemical sensitivity, spatial resolution & morphology & structure, varying probing depth, temporal resolution when possible.

Majority of these methods are based on interaction of the matter with photon, electron or ion radiation.

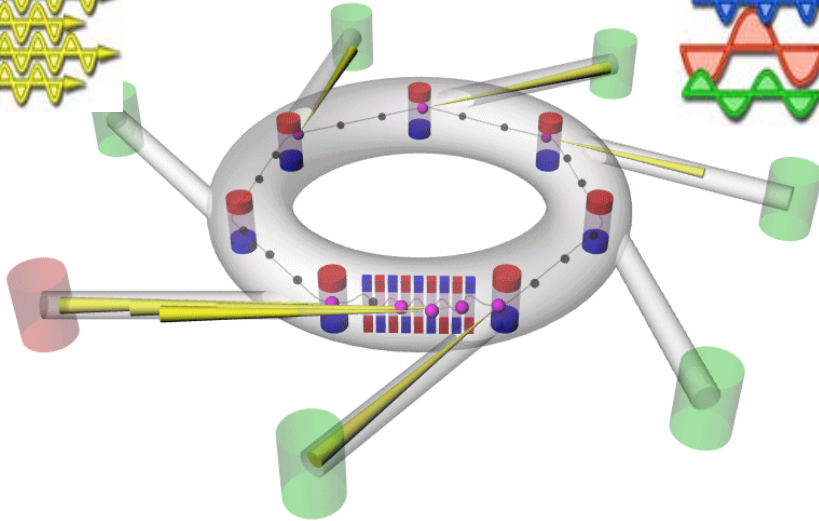


Why Microscopy needs Synchrotrons

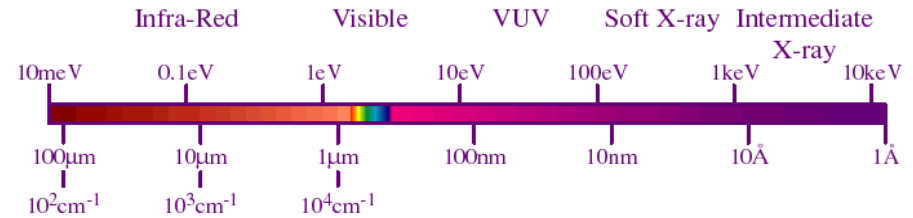
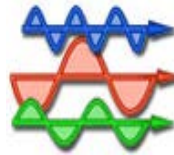
% coherent



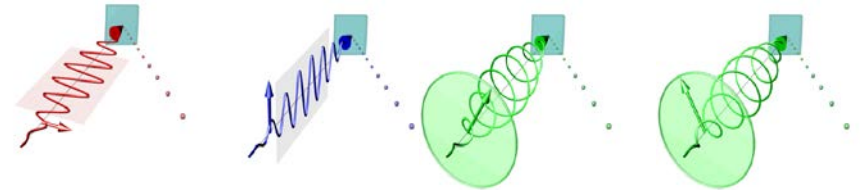
High Brightness



tunable



polarized

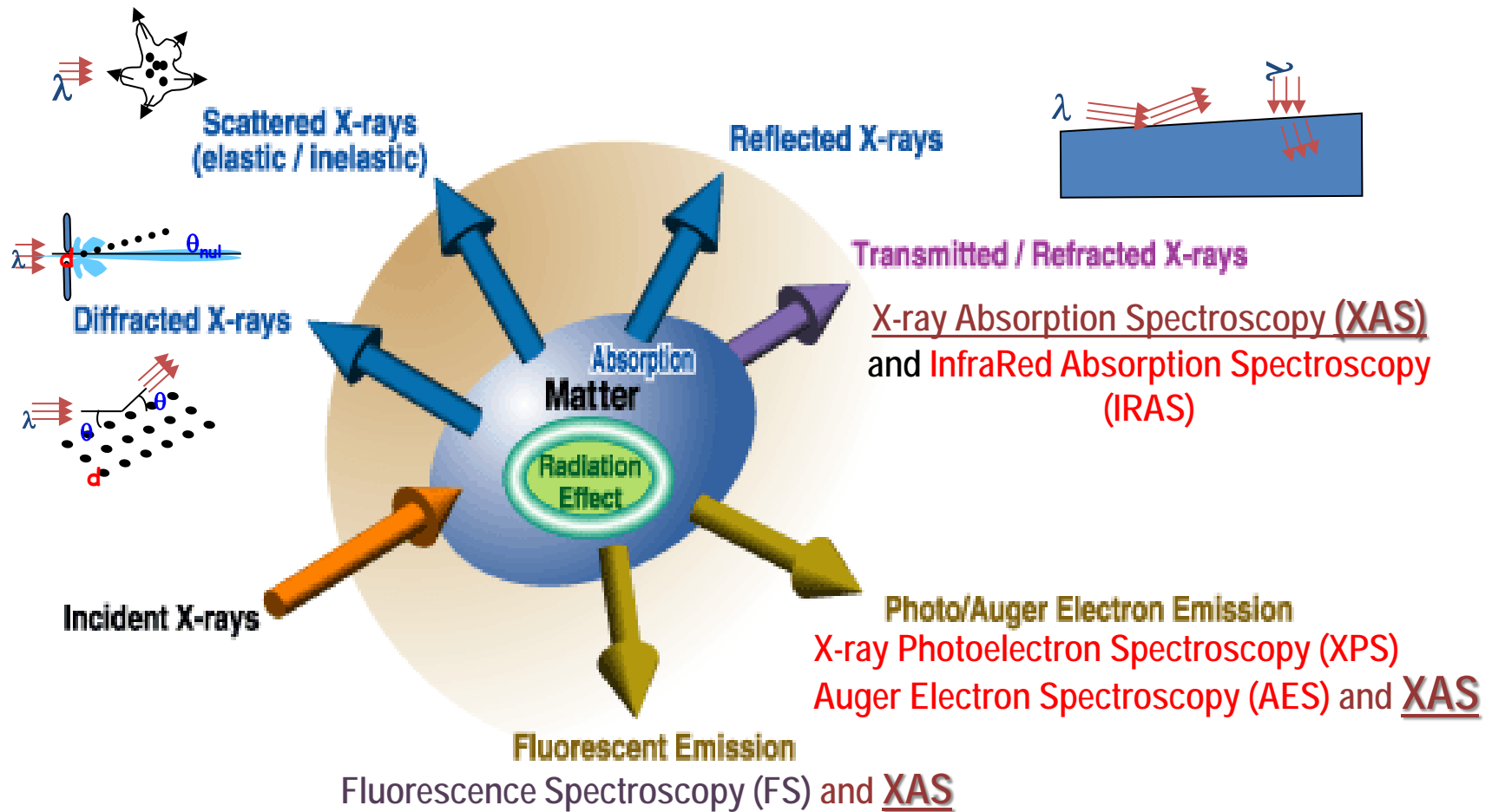


Synchrotron light advantages

- Very bright, wave-length tunable (cross sections and atomic edges), multiply polarized (dichroic effects, bonding orientation), partly coherent.
- Great variety of spectroscopies - elemental, chemical, magnetic information
- Variety of imaging contrasts based on photon absorption, scattering or spectroscopic feature.
- Higher penetration power compared to charged particles - less sensible to sample environment .



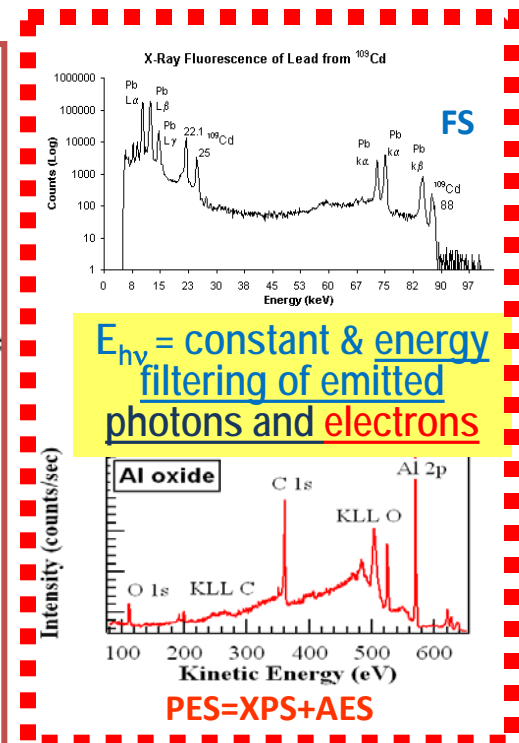
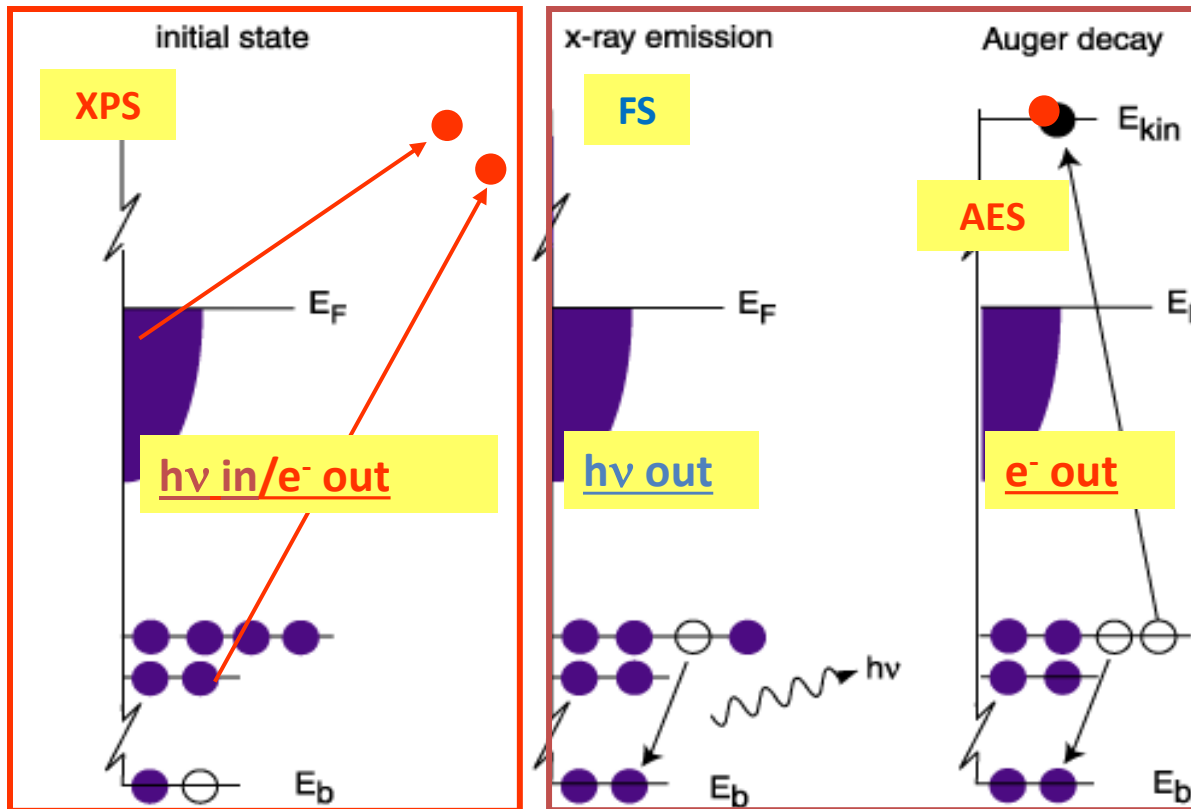
All methods using SR are based on the interaction of photons with the matter and find applications in all domains of science and technology





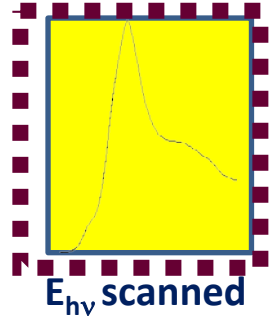
Spectroscopies @ synchrotron light sources: XPS-AES, XRF, XAS, RIXS

Photoelectric effect & de-excitation processes = chemical specific spectroscopies



XAS: based on absorption coefficient $\mu = f(h\nu - E_{\text{core}})$ and resonant electronic transitions governed by selection rules

e^- and $h\nu$ detection

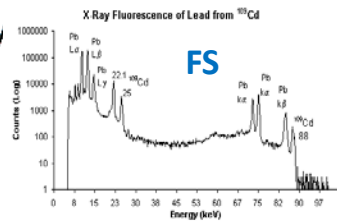
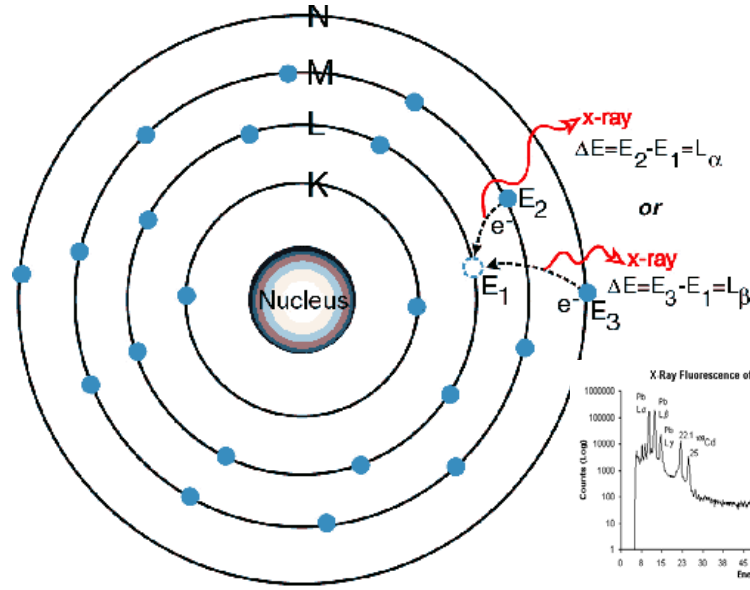
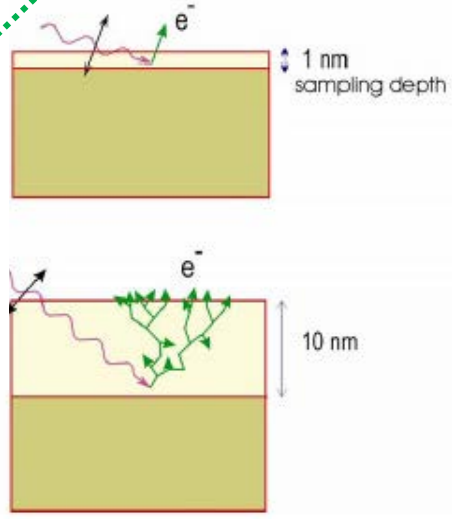
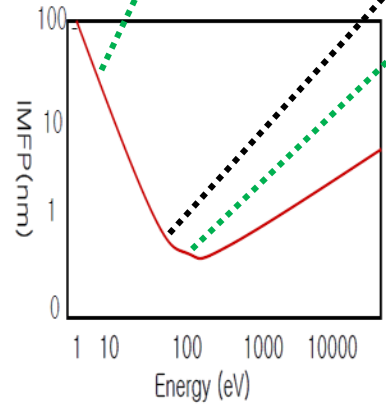
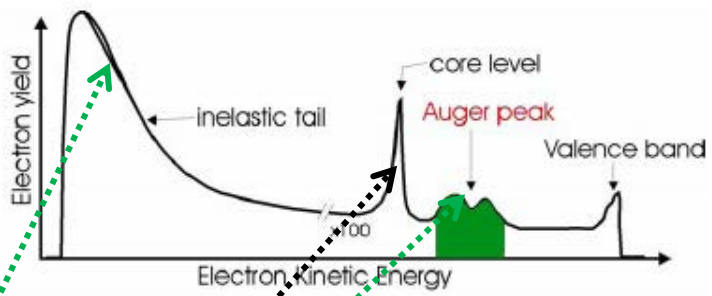




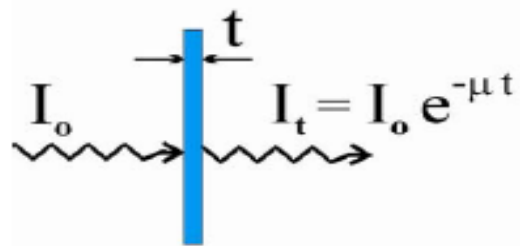
Sampling depths: depend on the detected signal (electrons or photons)

TEY & Auger electron emission (XAS), core & valence
PES: Probe depth 1- 10 nm

Fluorescence emission (XAS and FS):
Probe depth > 100 nm = f(E_{ph}, matrix)

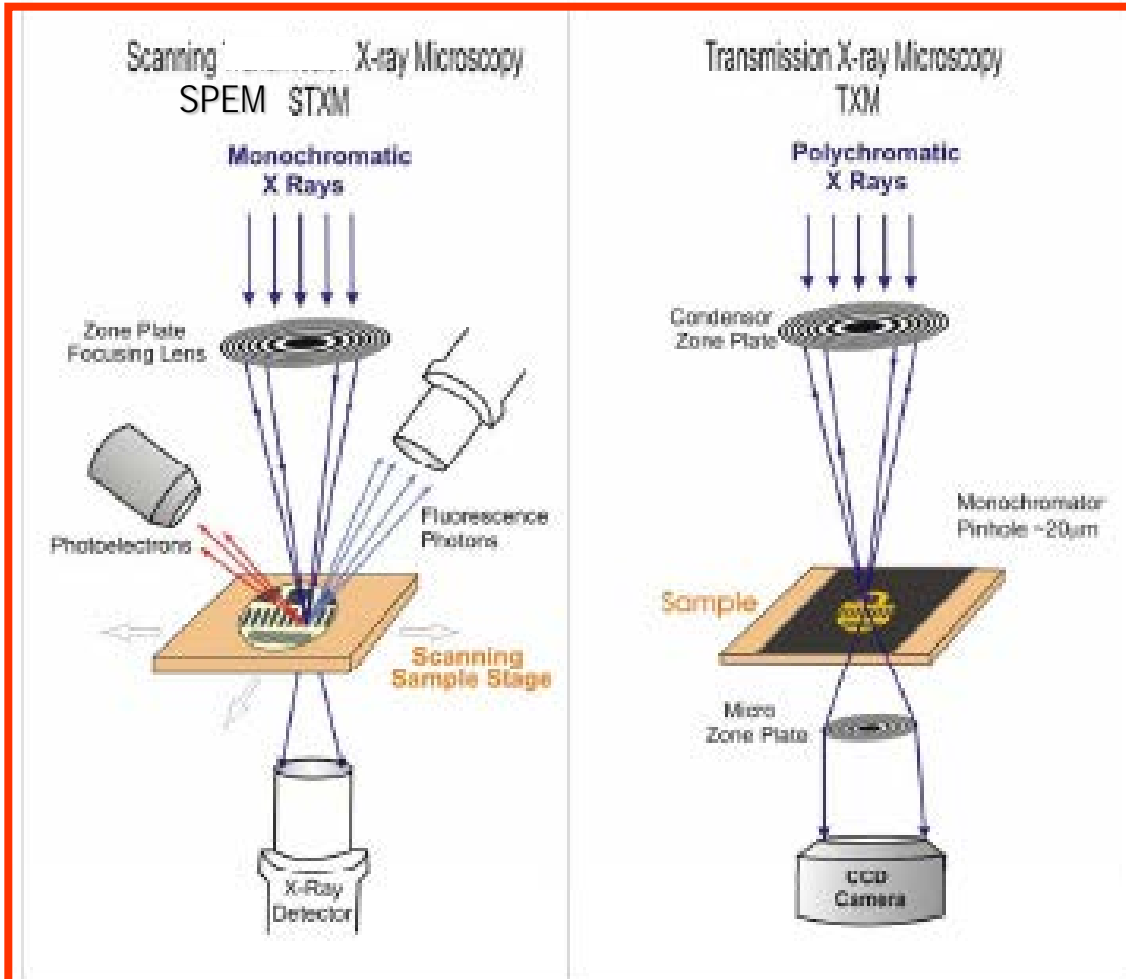


X-ray transmission: 'bulk'

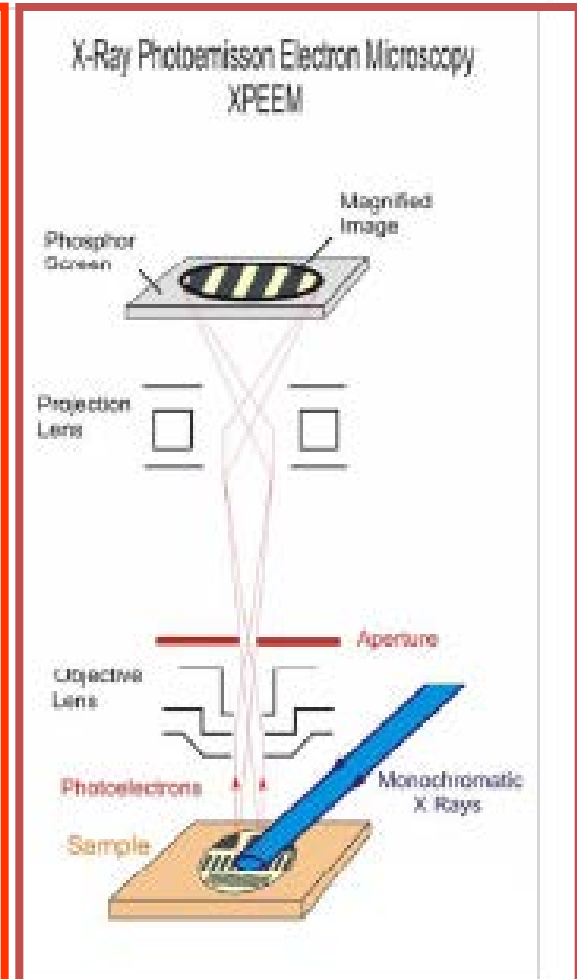




Microscopic Approaches, Adding Spatial Resolution: X-ray or electron optics



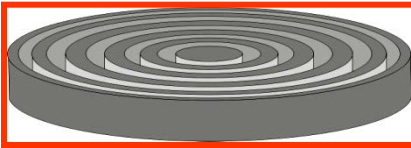
Lateral resolution provided by photon optics



Lateral resolution using electron optics

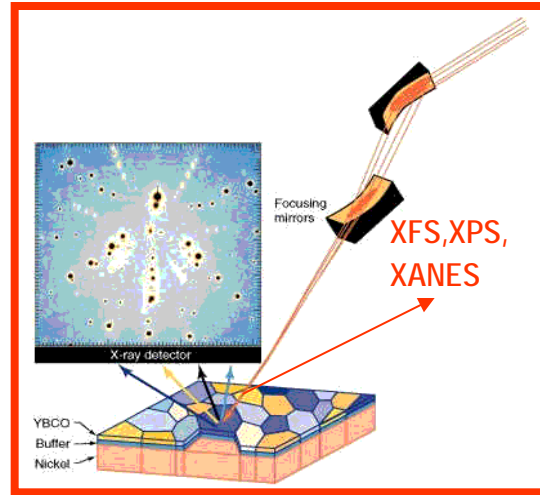


X-ray focusing optics: zone plates, mirrors, capillaries



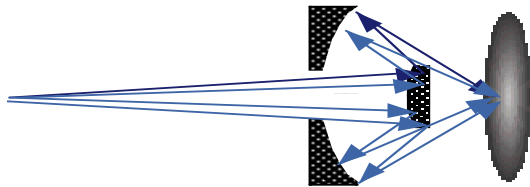
Zone Plate optics – circular grating with decreasing width:
from ~ 200 to ~ 10000 eV

Monochromatic:
Resolution achieved 15 nm in transmission



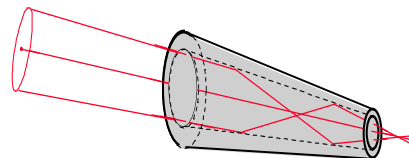
KP-B mirrors each focusing in one direction: soft & hard X-rays: ~ 100 nm

Soft & hard x-rays!
achromatic focal point, easy energy tunability, comfortable working distance
Resolution ≤ 100 nm



Normal incidence:
spherical mirrors with multilayer interference coating (Schwarzschild Objective)
Monochromatic, good for $E < 100\text{eV}$
Resolution: best ~ 100 nm

Capillary: multiple reflection concentrator



Hard x-rays ~ 8-18 keV
Resolution: > 3000 nm

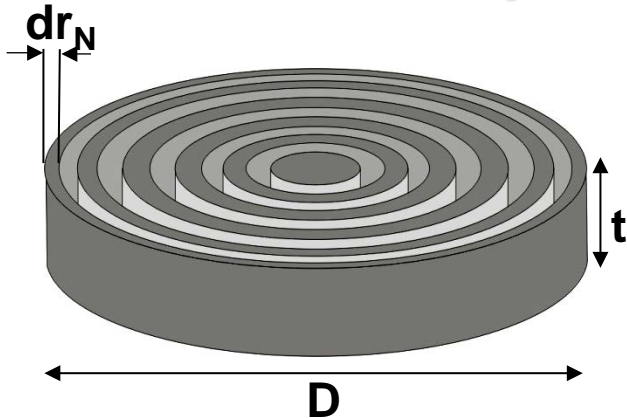
Refractive lenses



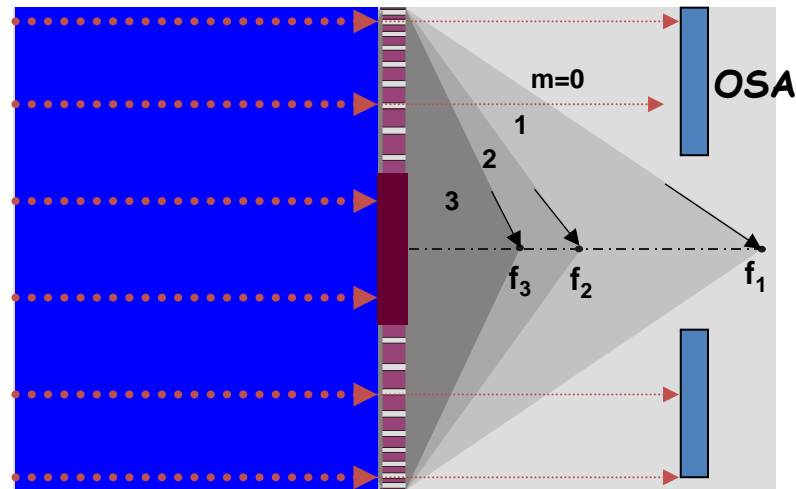
Hard x-rays ~ 4-70 keV
Resolution: > 1000 nm



Zone plate: circular diffraction grating of N lines with radially decreasing line width operating in transmission



$$f_m = D \cdot dr_N / \lambda$$



Important parameters:

Finest zone width, dr_N (10-100 nm) - determines

the Rayleigh resolution (microprobe size) $\delta t = 0.61 \lambda / (\theta) = 1.22 \delta r_N$

Diameter, D (50-250 μm), dr_N and λ determine the focal distance f .

Efficiency % of diffracted x-rays: 10-40% (4-25%)

Monochromaticity required: $\lambda/d\lambda \geq N$ (increases with $dr \downarrow$ and $D \uparrow$).



X-ray transmission microscope (TXM-FFIM)

Full-field X-ray imaging or "one shot" X-ray image acquisition can be considered as the optical analog to visible light transmission microscope.

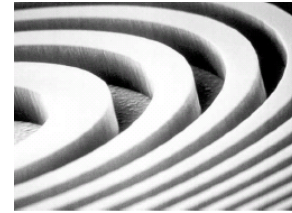
Günther Schmahl, 1st experiment DESY 1976



Aperture:
removes (i) unwanted diffraction orders and straylight, and serves (ii) with condenser as monochromator

X-ray light from a 2nd or 3rd generation light source

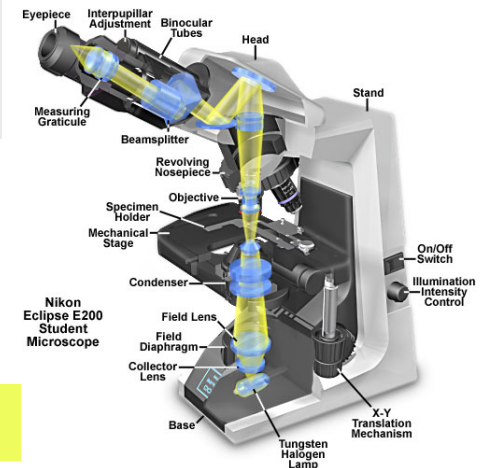
Condenser illuminating the object field



Objective ZP to magnify the image onto the detector

Specimen environment: to be adapted to application

CCD camera



Resolution achieved better than 15 nm.

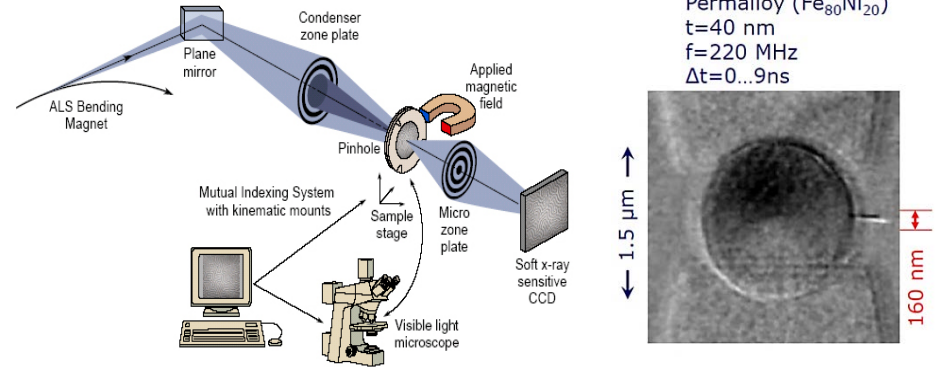
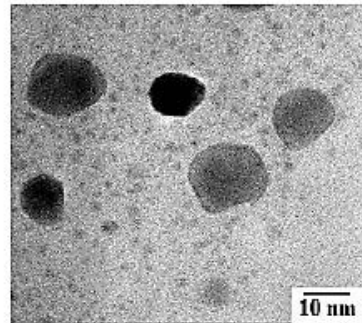
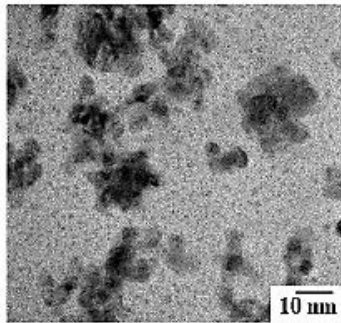


Following dynamic processes during temperature treatment, applying magnetic/electric field or pumping with optical lasers X

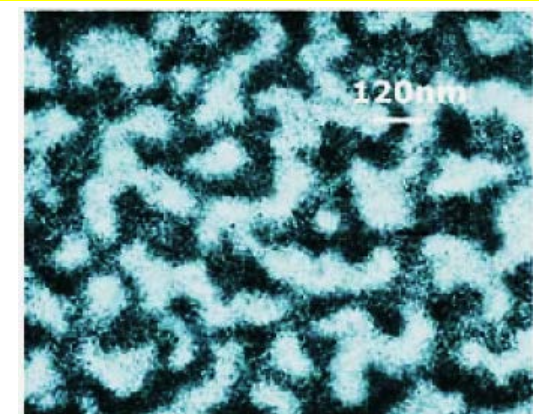
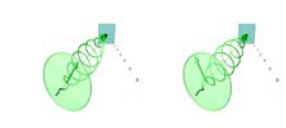
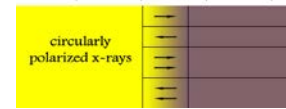
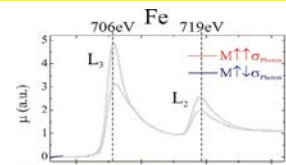
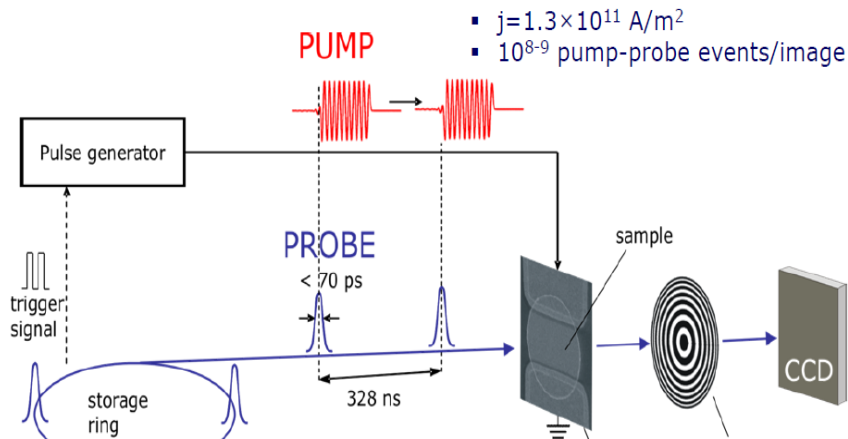
Fe₃₈Rh₆₂ nanoparticles

as-deposited

after annealing

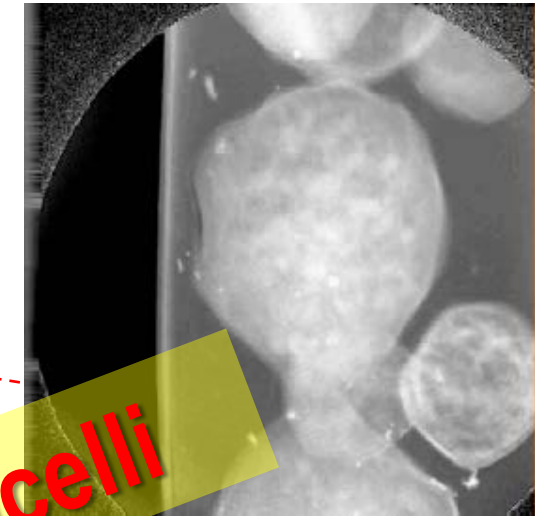
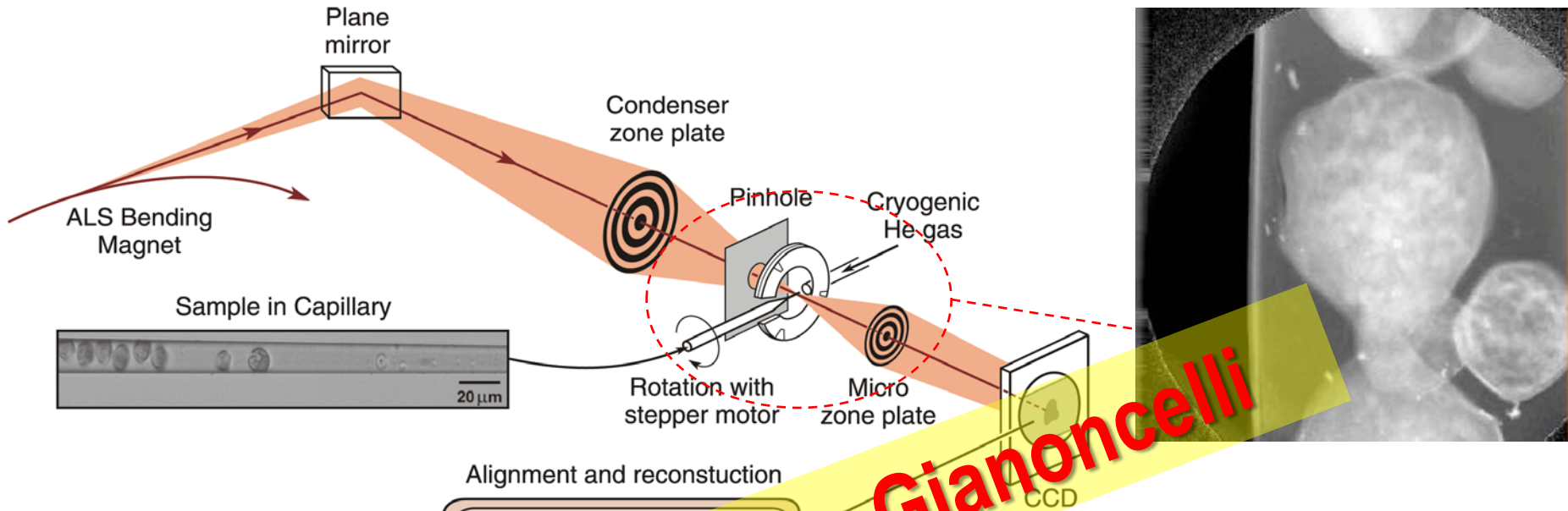


XAS-XMCD X-Ray Magnetic Circular Dichroism





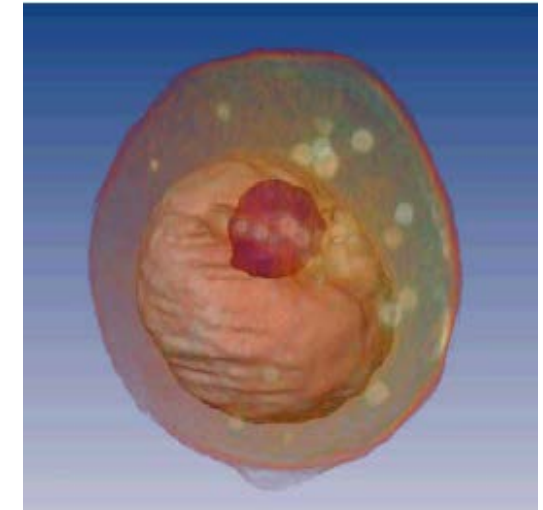
Cryogenic 3D imaging of biological cells



Alignment and reconstruction



Lecture: Alessandra Gianoncelli

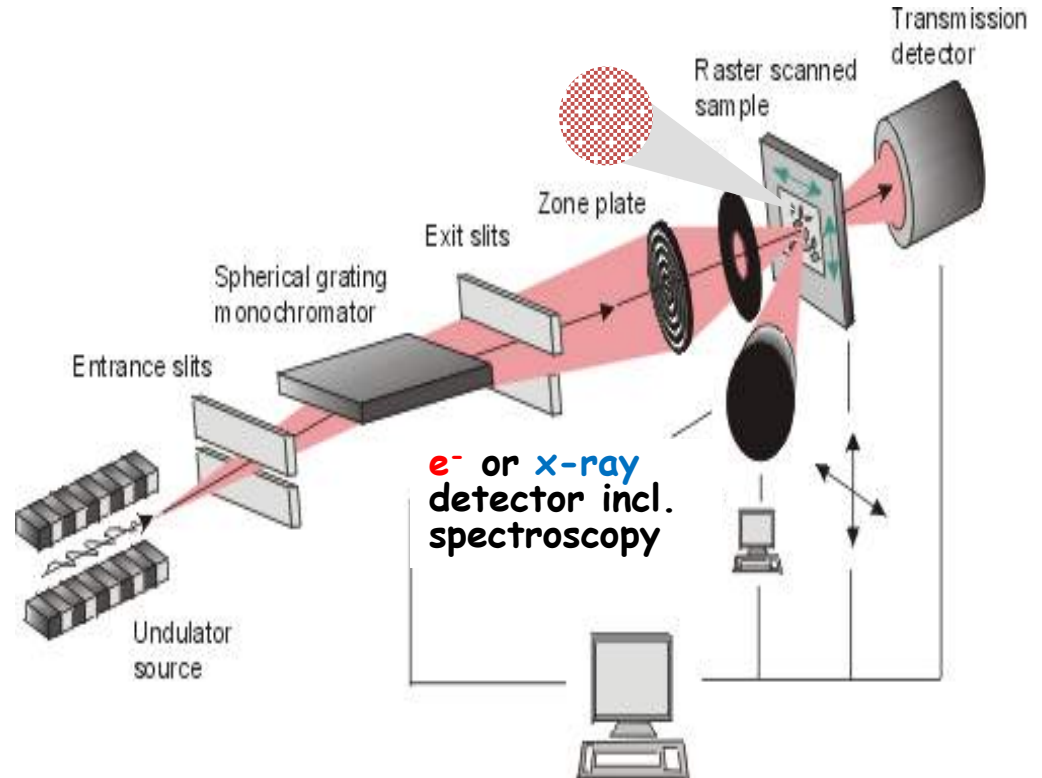




X-ray Scanning microscopy: uses focusing x-ray optics (preferred zone plates)

Works in Transmission and Emission + microspot spectroscopy

Janos Kirz, 1st operating STXM 1983
SPEM 1990

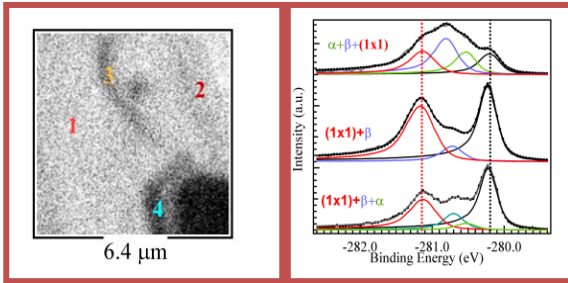


Can use all detection modes!
Resolution achieved 25 nm in transmission.



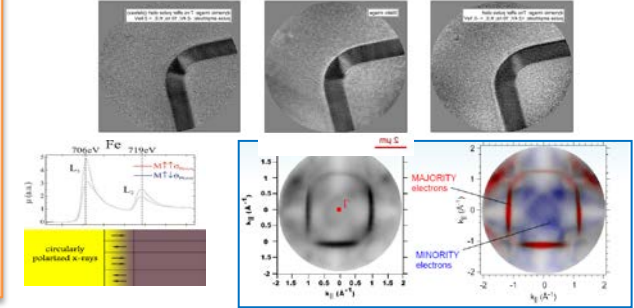
Microscopy Approaches @ ELETTRA storage ring: X-ray or electron optics; X-ray or electron detection

PES Imaging and microspectroscopy

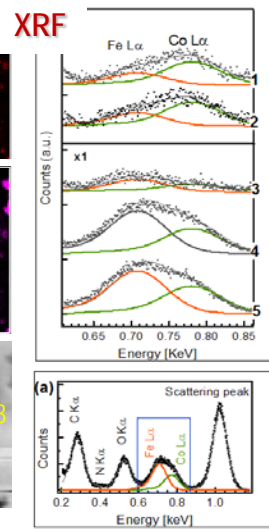
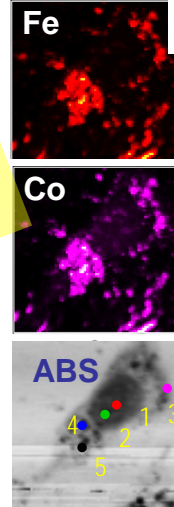
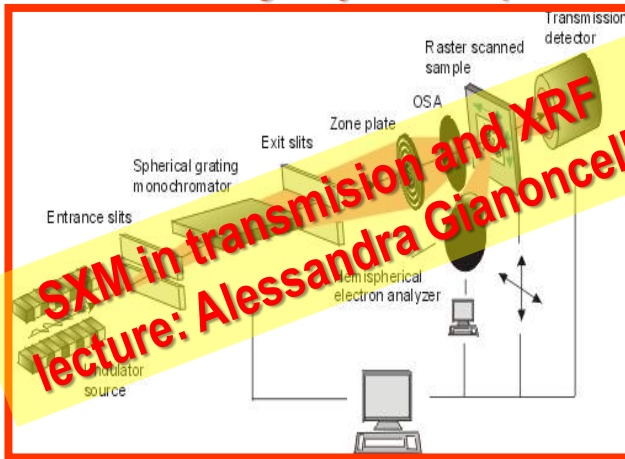


XRF, XPS, XAS = elemental and chemical information
X-ray transmission and scattering (phase contrast) - morphology
Topology – electron emission

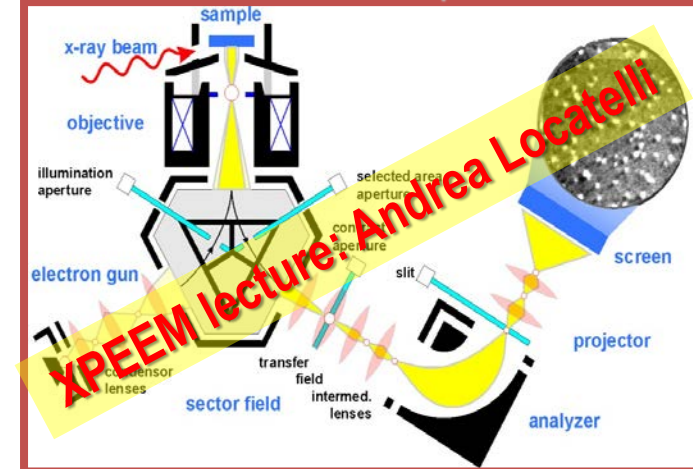
Magnetic imaging



3 Scanning x-ray microscopes



2 XPEEMs – Elettra & FZJ + Spin filtered detection



The image contrast can provide:

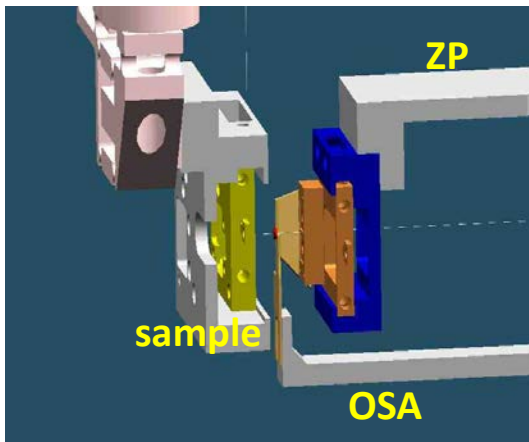
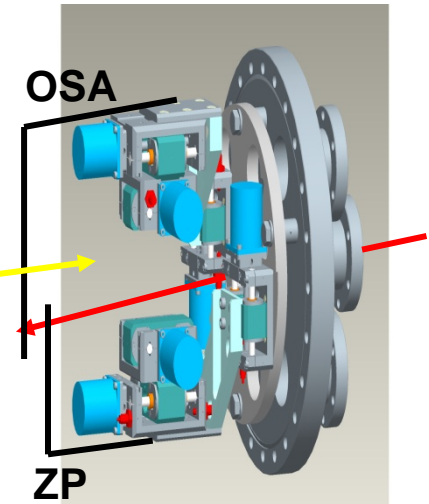
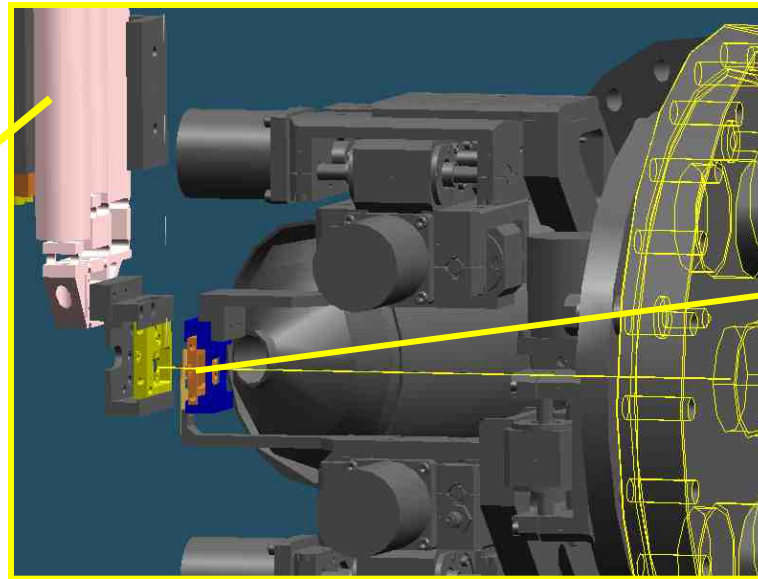
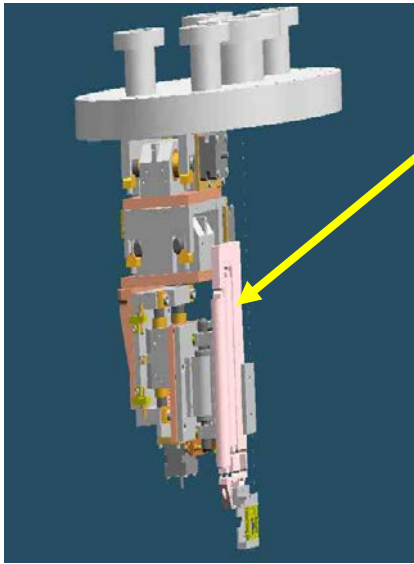
- Morphology: density, thickness (transmission)
- Element presence and concentration- e^- , $h\nu$;
- Chemical state, band-bending, charging e^- ;
- Magnetic spin or bond orientation – e^- , $h\nu$



Microspectroscopy:
 μ -XPS, μ -XANES, μ -XRF in selected areas from the images: detailed characterization of the chemical and electronic structure of coexisting micro-phases.



Layout of SPEM: Focusing optics (ZP, SO or K-B), sample and positioning systems



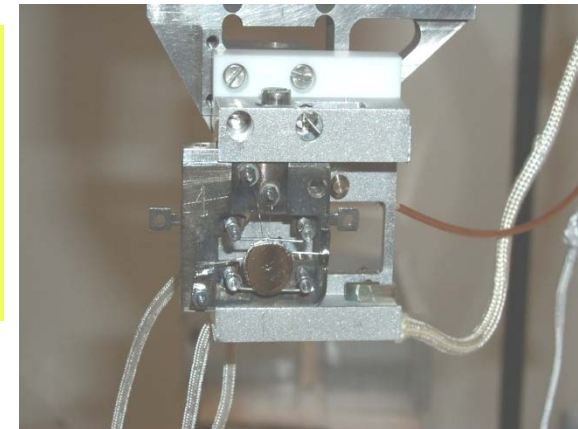
Spatial resolution in electron emission limited by the sample-to-optics distance !

$$f_m = D_x dr_x E_{ph} / 1240$$

~10 mm for soft X rays

$$DOF = \frac{\delta r}{D} f_m$$

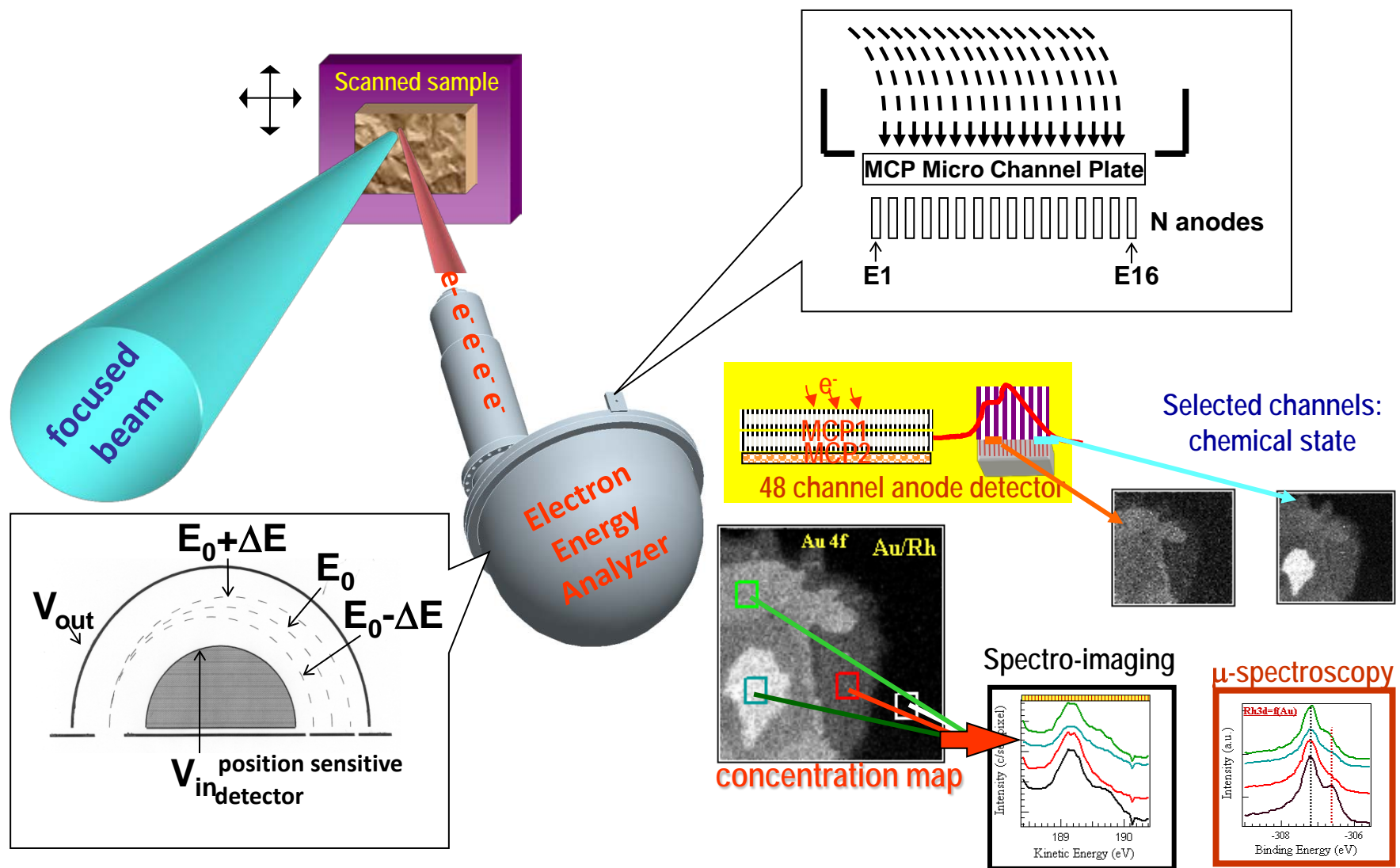
Typical: 5-15 μm





SPEMs energy-filtering electron analyzers

MCD developed @ ELETTRA

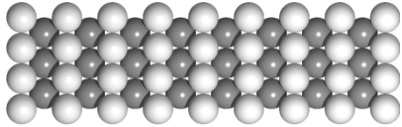




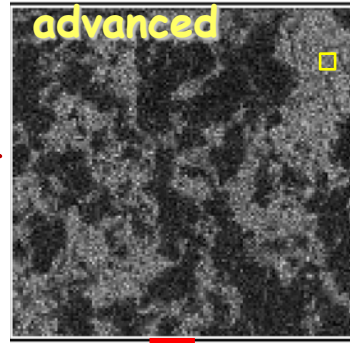
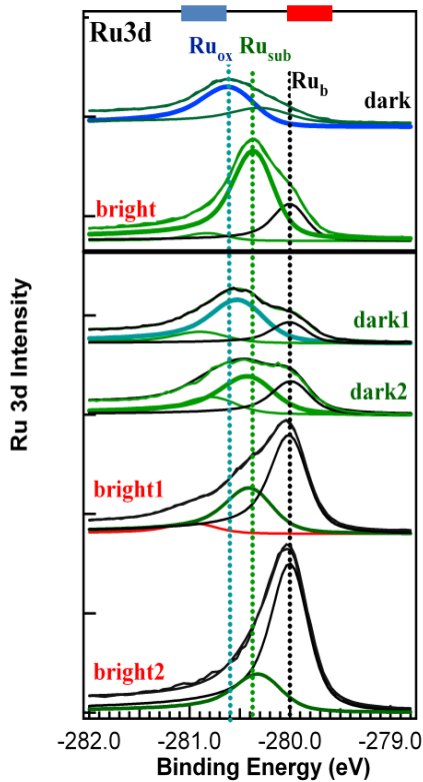
Model catalyst systems studied with SPEM: single crystals and supported metal particles on MgO

Oxidation states: Ru(Rh) 3d maps & Ru(Rh)3d μ -PES

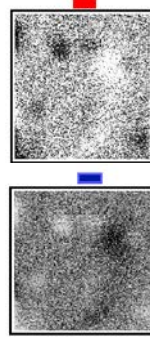
R. Blume et al, JPC B 109, 14058; P. Dudin et al, JPC B 109, 13649; 125, 94701



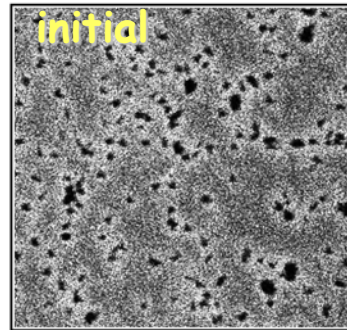
$\text{Ru}(0001) \equiv \text{Rh}(110)$



Ru3d metallic state

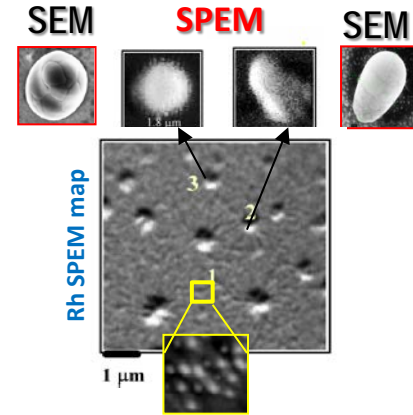


2 μm

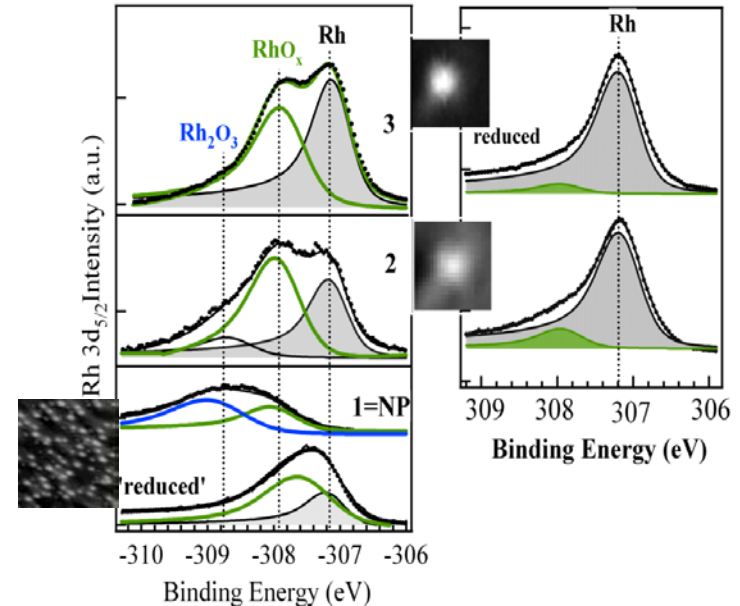


32 μm

'Transient Surface Oxide' (TSO) ~ 10-12 Å; Ru(Rh) oxides nucleate inside the 'amorphous' TSO



No simple size effect

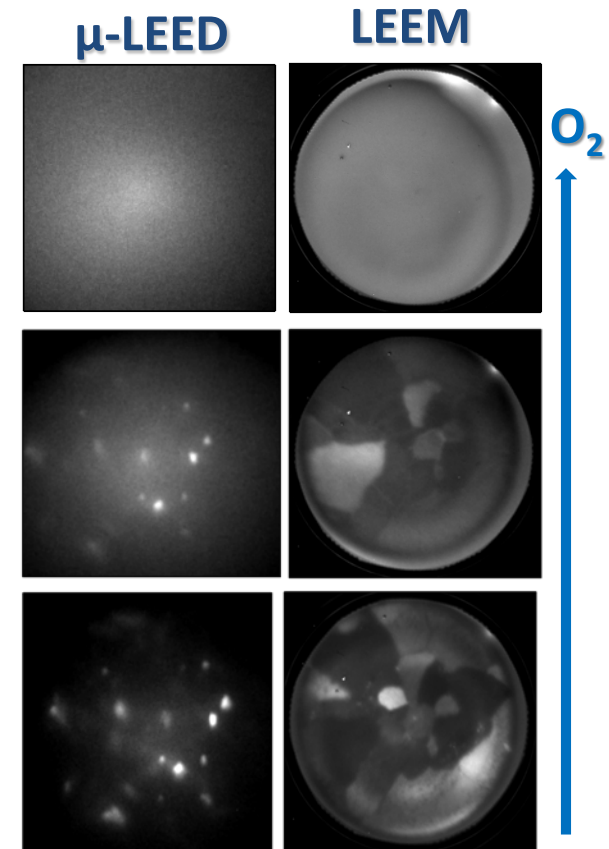
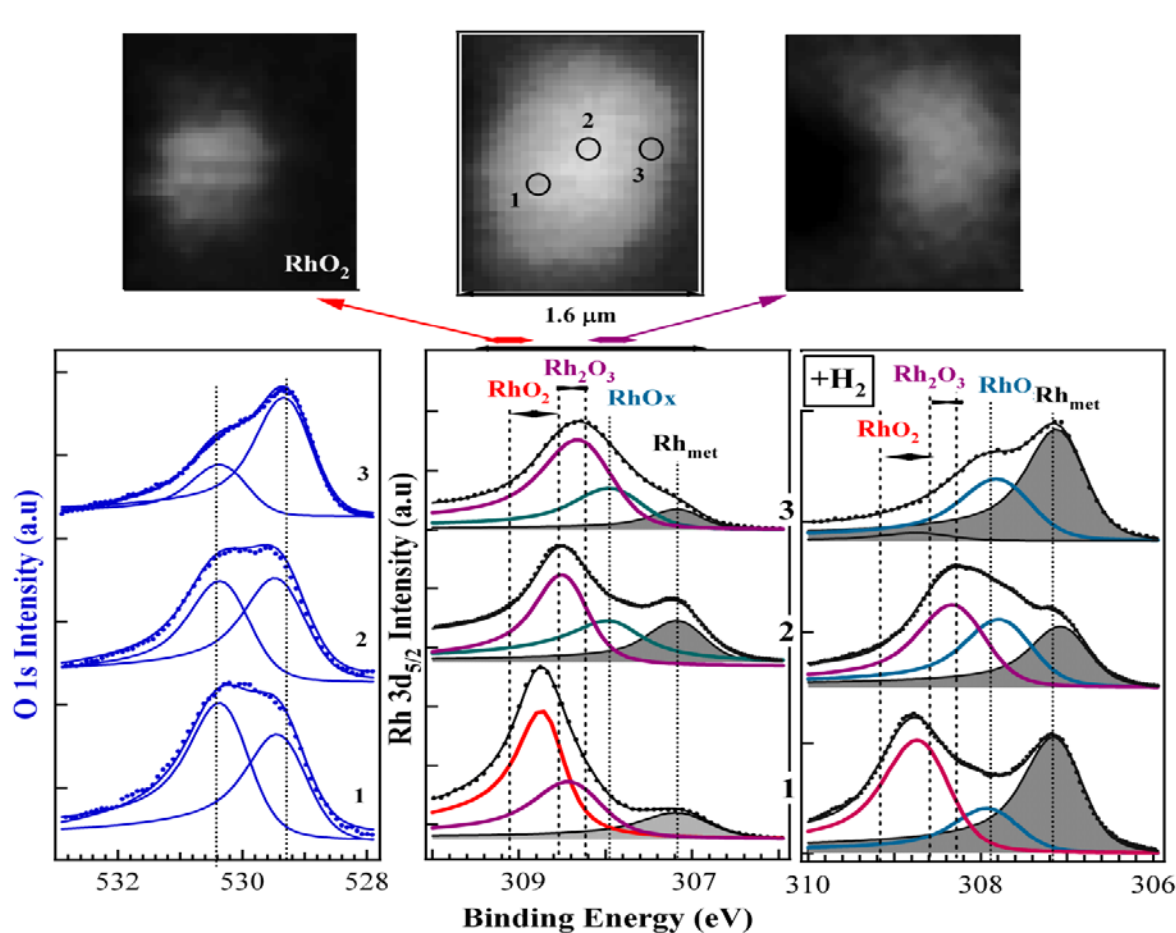


P. Dudin et al, JPC C 1112, 9040;
M. Dalmiglio JCP C, 114 16885

Maya Kiskinova

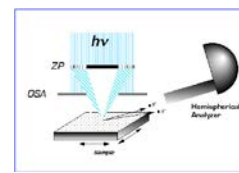


Correlation of the μm -particle reactivity to its complex surface structure: **SPEM - LEEM**

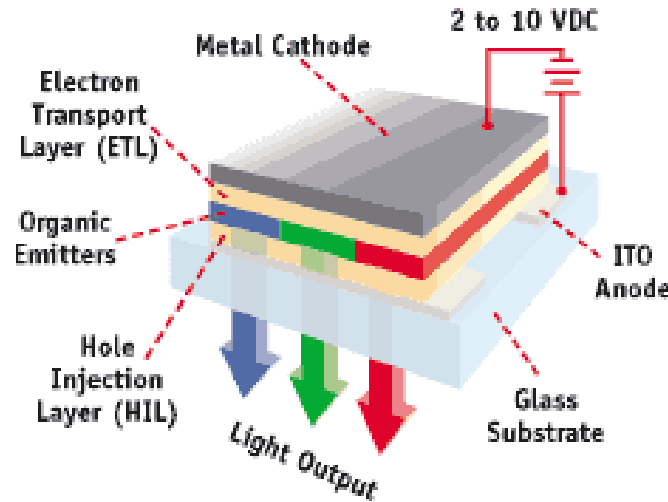
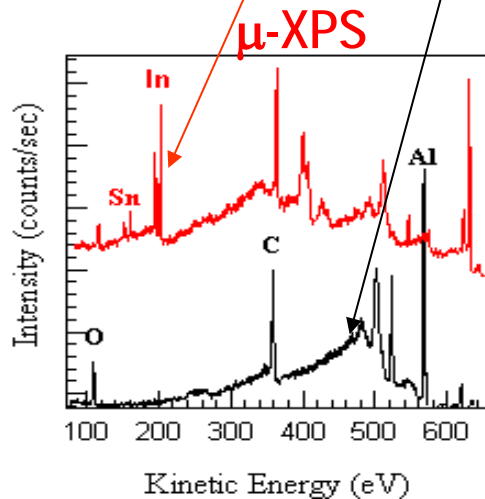
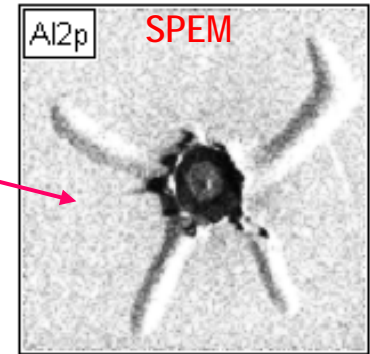
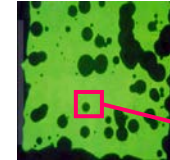
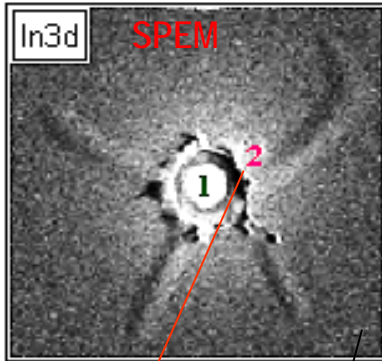


- 'Inhomogeneous' reactivity in $\mu\text{-Ps}$ related to the surface morphology;
- Structural evolution upon oxidation ends with a disordered oxide

Degradation of organic light emission devices: mechanism revealed by 'in-situ' SPEM



OLED exposed to ambient: moisture? supposed to be the damaging factor



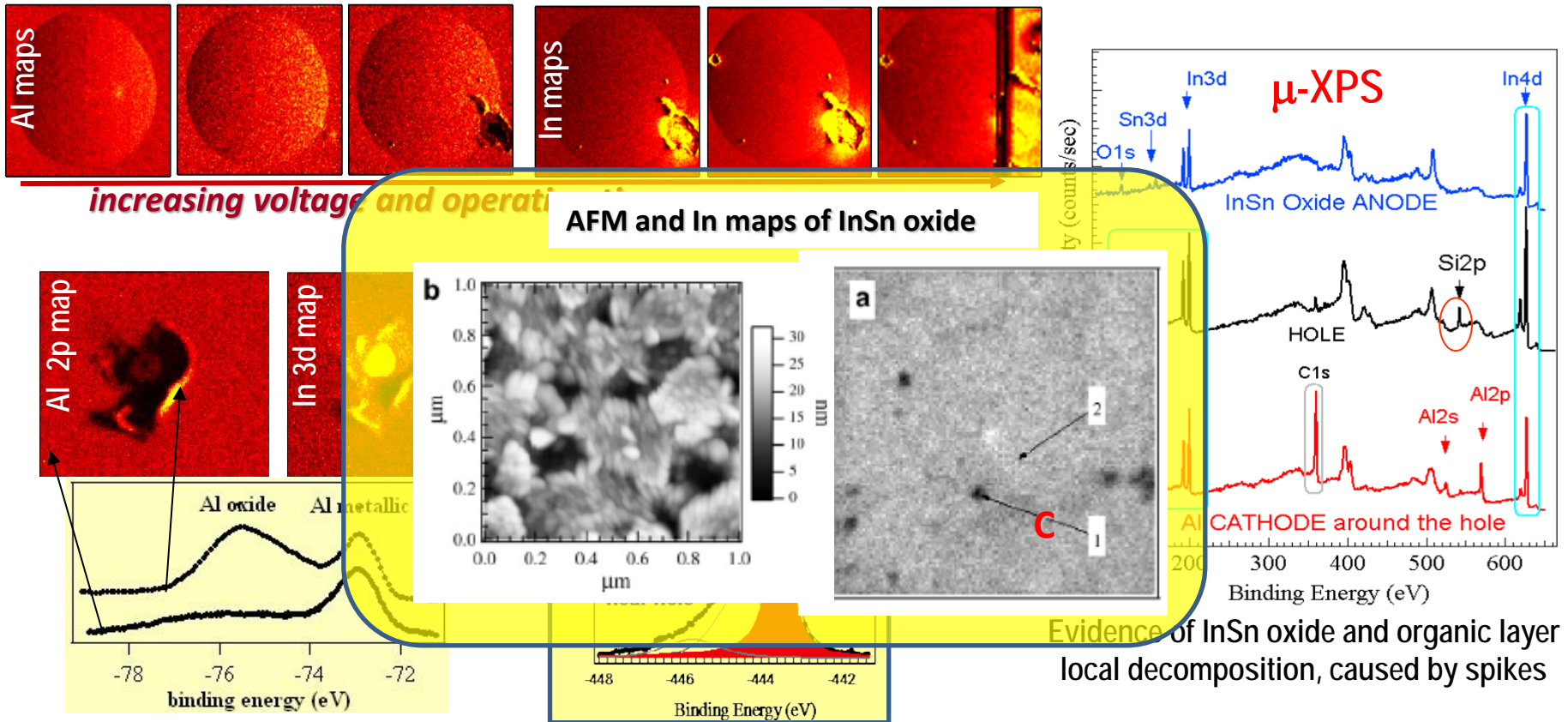
Topographic features due to fracture: clearly seen as enhancement and shadowing of the emitted electrons

Chemical imaging & μ -XPS revealed anode material (In and Sn) deposited around the hole created in the Al cathode of OLEDs.



'In-situ' imaging of the local deformation and fracturing of the OLED cathode surface

"Clean" failure experiment: OLED growth and operated in the SPEM (UHV ambient)

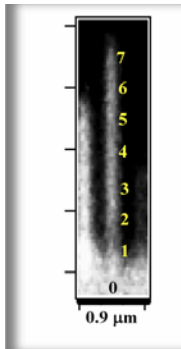
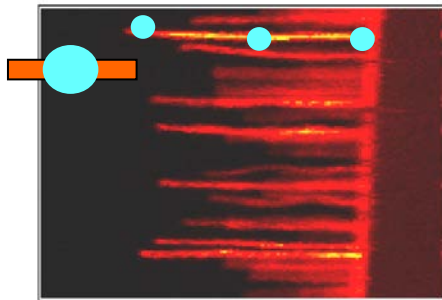
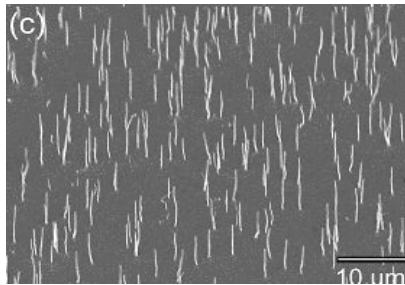


Lateral variations of the surface topography and chemistry of the InSn oxide anode films suggested as the major reasons for the device failures.

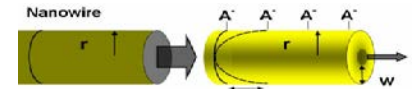
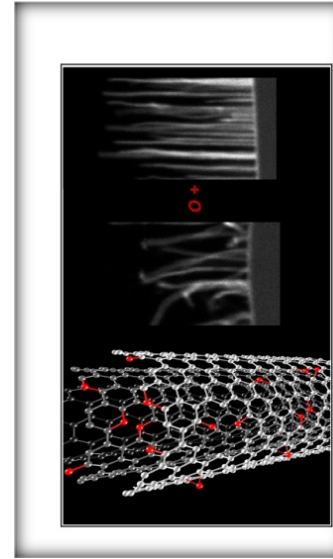
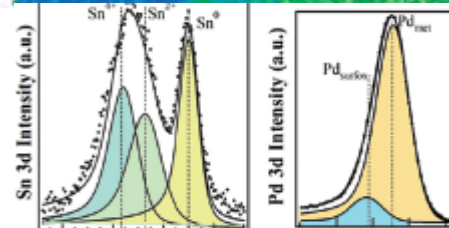
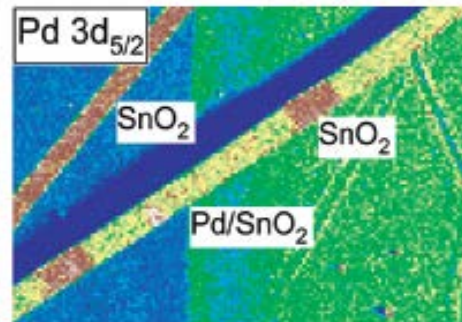
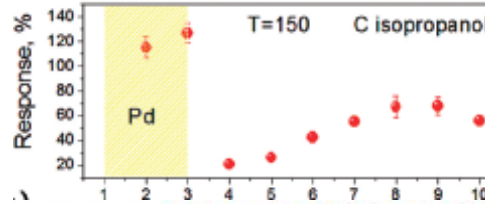
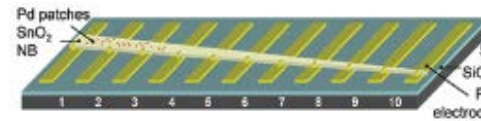


Exploring the properties of individual and free-standing nano-structures

Low density NWs



NB electronic nose



Imaging and Spectroscopy of Multiwalled Carbon Nanotubes during Oxidation: Defects and Oxygen Bonding
 By Alexei Barinov^{1*}, Luca Gregoratti, Pavel Dudin, Salvatore La Rosa, and Maya Kiskinova¹
 PRL 99, 046803 (2007)
 PHYSICAL REVIEW LETTERS
 Defect-Controlled Transport Properties of Metallic Atoms along Carbon Nanotube

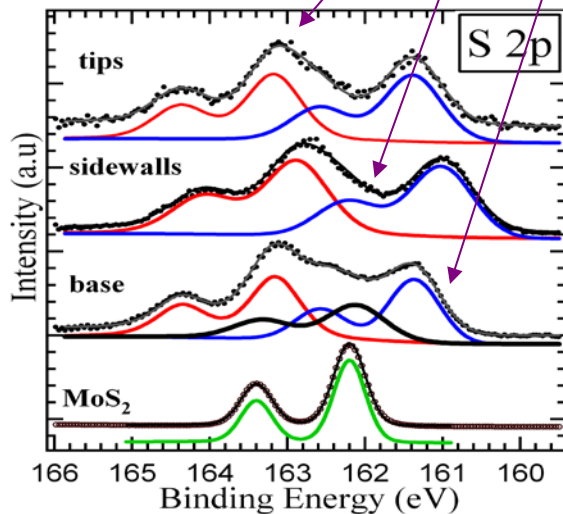
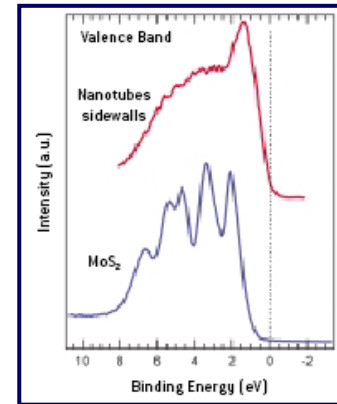
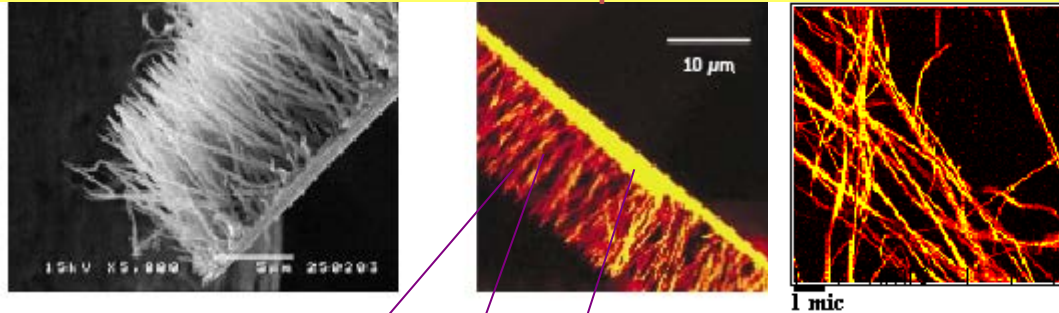
Contactless Monitoring of the Diameter-Dependent Conductivity of GaAs Nanowires
 Fauza Jabbar^{1,2}, Silvia Rubin¹ (ICSI), Faucino Martelli¹, Alfonso Franco^{1,2}, Andrea Goldoni¹, and Maya Kiskinova¹ (ICSI)
 Nano Res. 2010, 3(10): 706-713

Single-Nanobelt Electronic Nose: Engineering and Tests of the Analytical Element
 Victor V. Sotnikov^{1,2}, Evghenii Stepanov¹, Martin Sommer¹, Michael Baum¹, Ekaterina Kiskinova¹, Wilhelm Hähnle¹, and Luca Gregoratti¹, Maya Kiskinova¹, and Andrea Goldoni¹
 2010



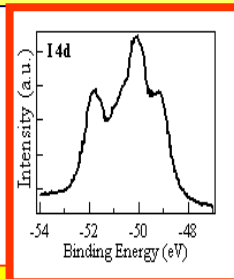
SPEM characterization of MoS₂-nanotubes

Twisted chiral bundles of Mo-S individual cylinders:
Mo 3d maps



? It that due to the low dimensionality the S 2p, Mo 3d and VB spectra are position-dependent?

This should indicate electronic properties significantly different those of the MoS₂ crystal.



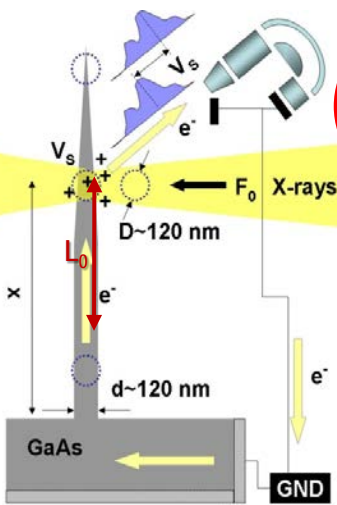
SPEM revealed I (used as a carrier) in interstitial positions between the tubes bonded to the outer S atoms. ? Is the role of I ??



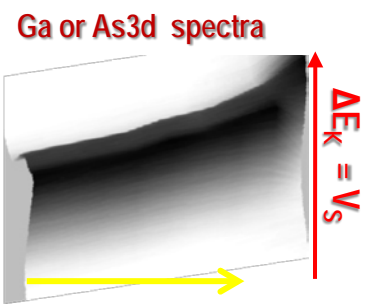
GaAs NWs conductivity measured with SPEM: non-ohmic behavior with reducing diameter, environment effects, effect of growth conditions

$$E_K = E_{K0} \pm E_{BB} \pm E_{SPV} - V_s$$

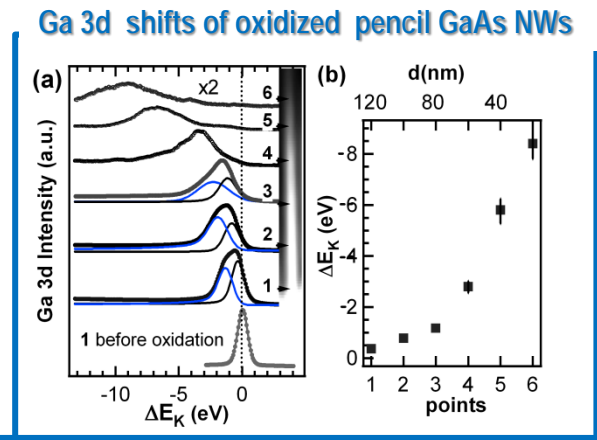
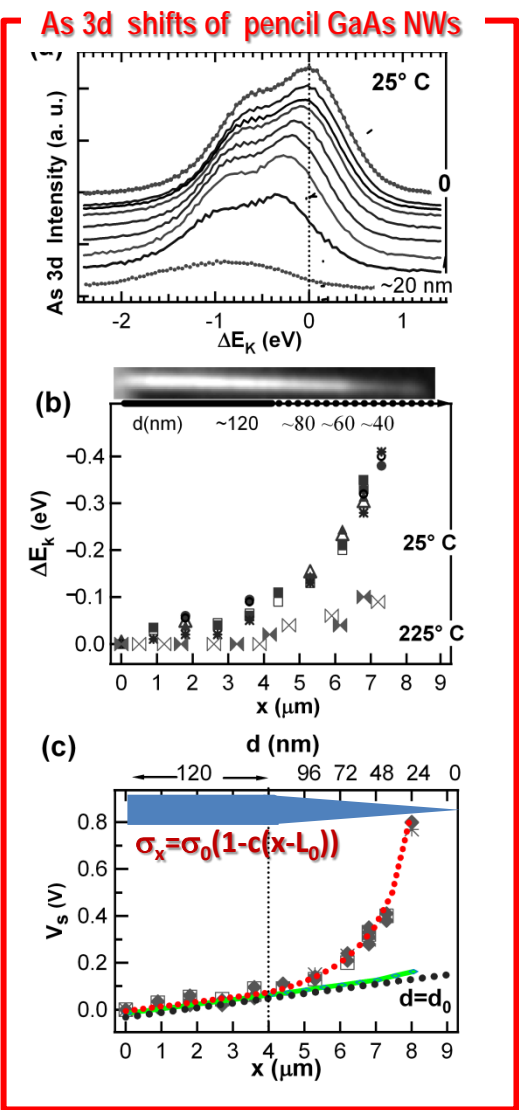
$$V_s = f(\text{Ohmic neutr. current})$$



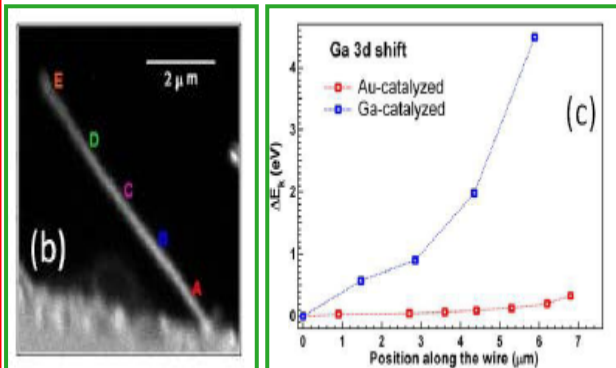
$$V_s = \frac{4\delta \cdot F_{ph} \cdot x \cdot \sigma}{\pi \cdot d_0^2}$$



- ❖ Conductivity of pencil-like NWs: non-ohmic behavior as a function of d.
- ❖ The data fit to linear decrease of σ with decreasing d > confirms size effects



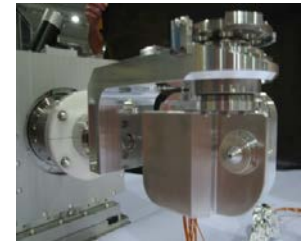
Oxidation: drastic reduction in the carrier density : transport properties = f(ambient)



Metal catalyst > drastic conductivity increase



SPEM - μ -ARUPS



NANO LETTERS

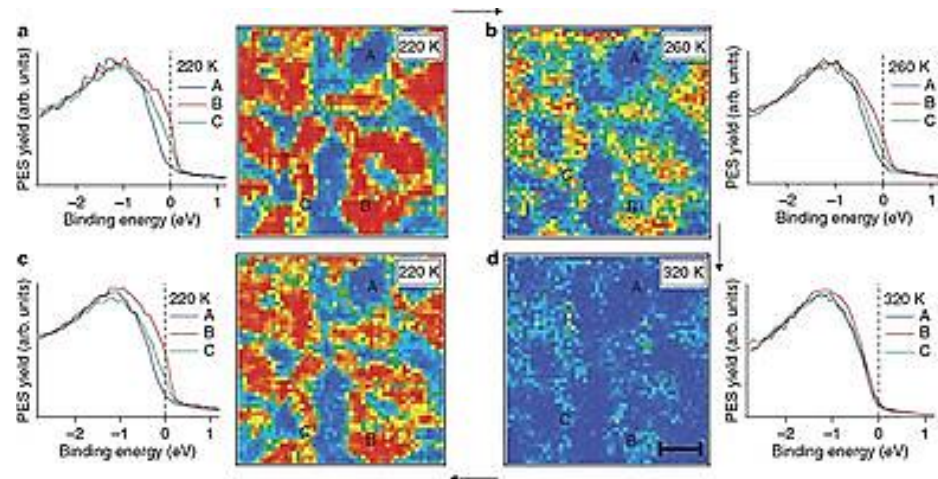
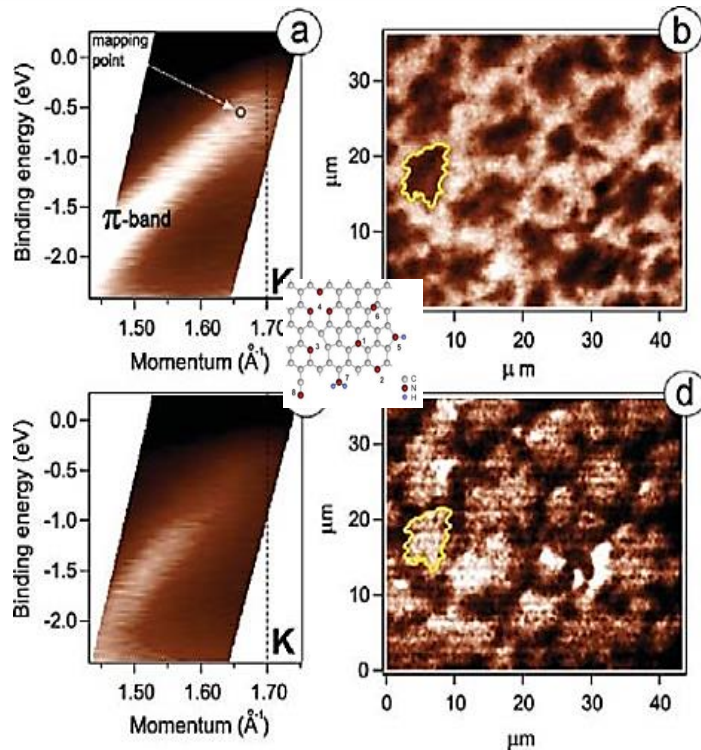
pu

Nitrogen-Doped Graphene: Efficient Growth, Structure, and Electronic Properties

D. Usachov,^{*,†} O. Vilkov,[†] A. Grüneis,^{*,§} D. Haberer,[†] A. Fedorov,[†] V. K. Adamchuk,[†] A. B. Preobrajenski,^{||} P. Dudin,[†] A. Barinov,[†] M. Oehzelt,^{||} C. Laubschat,[†] and D. V. Vyalikh

μ -ARPES of quasi-free standing N-doped graphene: EVIDENCE OF COEXISTENCE OF AT LEAST TWO DOMAINS ROTATED BY 30 deg: found T-dependence and extinctions of the B-domains.

Metal-insulator transition in Cr-doped V_2O_3 with decreasing T, microscopic domains become metallic and coexist with an insulating background.



S. Lupi *et al.*, Nature Comm. 1, 105 (2010)



Ongoing μ -PES developments

THE CHALLENGE:

In-situ measurements of nano-structured matter under realistic ambient conditions needs to overcome the UHV limitations



J. Kraus et al, *Nanoscale* 2014, DOI: 10.1039/c4nr03561e

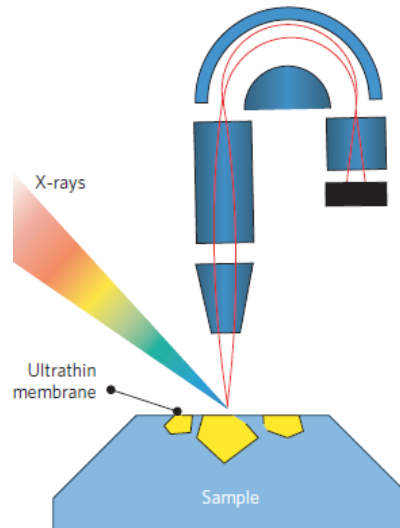
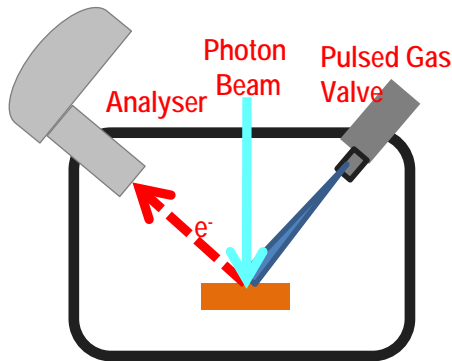
nature nanotechnology

ARTICLES

PUBLISHED ONLINE: 28 AUGUST 2011 | DOI: 10.1038/NANO.2011.130

Graphene oxide windows for *in situ* environmental cell photoelectron spectroscopy

Andrei Kolmakov^{1*}, Dmitriy A. Dikin², Laura J. Cote², Jiaying Huang², Majid Kazemian Abyaneh³, Matteo Amati³, Luca Gregoratti³, Sebastian Günther⁴ and Maya Kiskinova³



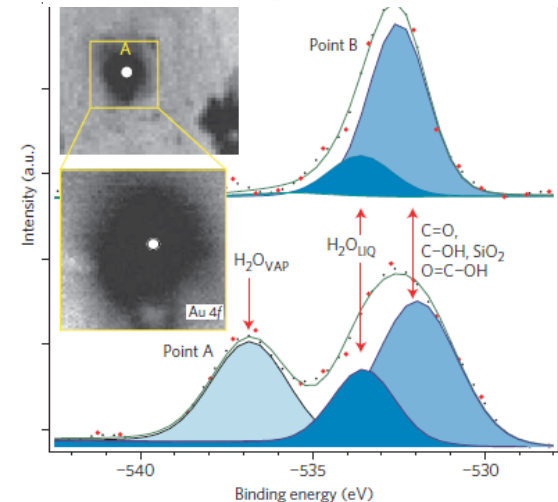
G-GO windows: robust, impermeable, transparent

Gas or Liquid sealant
SiN window with μ -hole on Si

**Pulsed supersonic beam:
Dynamic local pressure of 10^{-2} mbar using high freq pulsed dosing valve + nozzle**

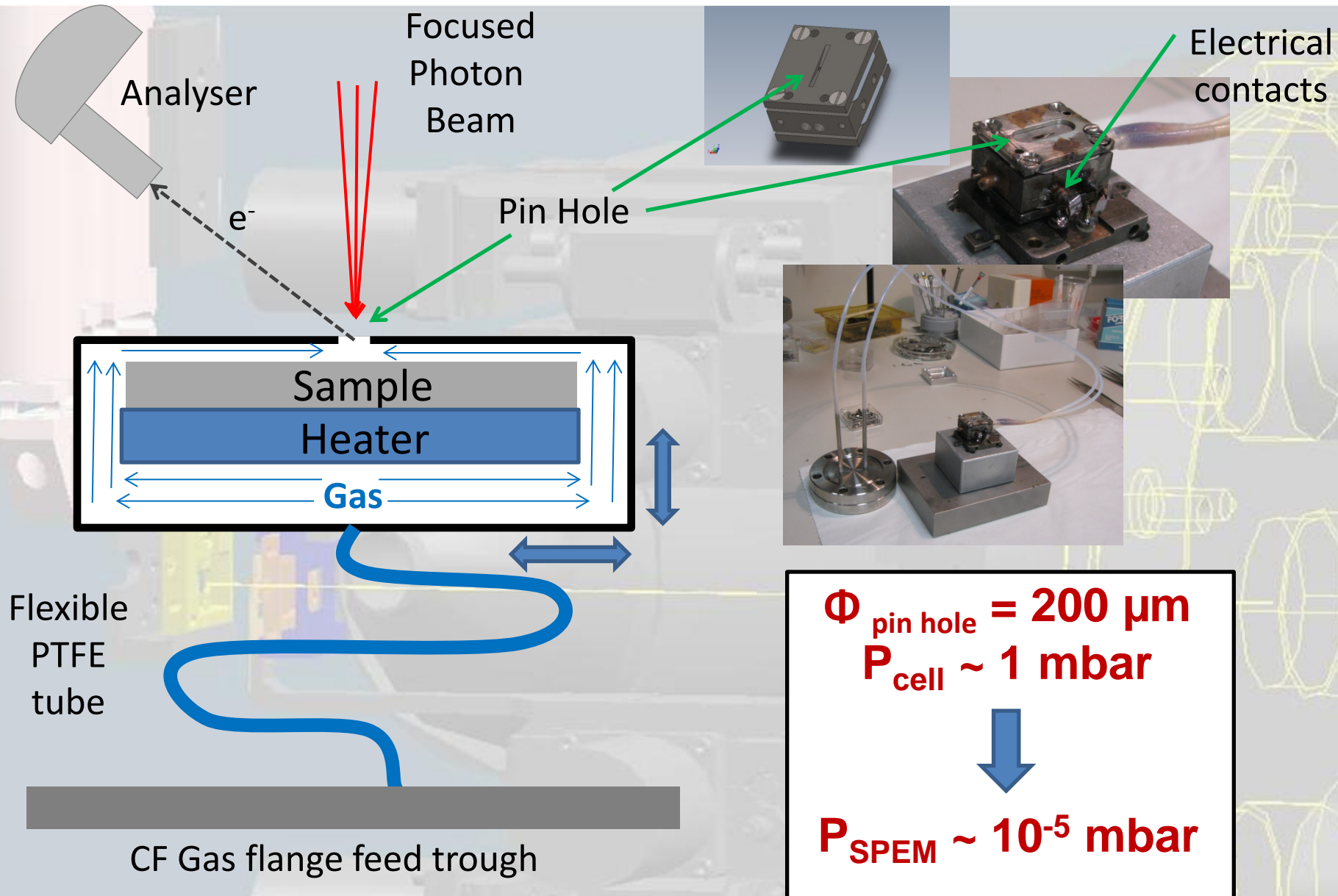
M.Amati et al, *J. Instr.*8, 2013, T05001

3 M NaI aqueous solution





Static high pressure XPS





Classical X-ray imaging and spectromicroscopy: brief outline

SURFACES & INTERFACES:

XPEEM and SPEM

PHOTON-IN/ ELECTRON-OUT

(probing depth= $f(E_{el})$ max ~ 20 nm)

Spectroscopy (XPS-AES-XANES)

ONLY CONDUCTIVE SAMPLES

Total e⁻ yield
(sample current)

- **Chemical surface sensitivity:**
Quantitative μ -XPS (0.01 ML)
- **Chemical & electronic (VB) structure**

XANES

BULK Information

STXM/SPEM & TXM

PHOTON-IN/PHOTON-OUT

(probing depth = $f(E_{ph}) > 100$ nm)

(Spectroscopy – XFS or XANES)

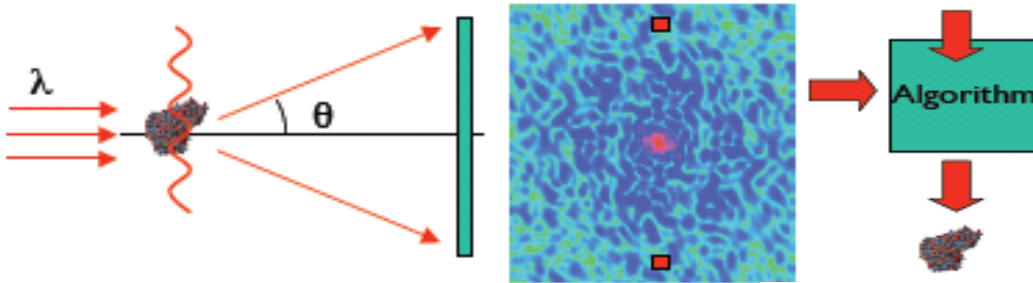
Total hv yield,
Transmitted x-rays

Chemical bulk sensitivity
Quantitative μ -XFS
Trace element mapping

Imaging: spatial and temporal limitations

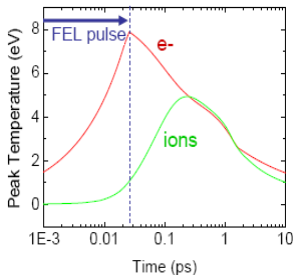
- **Classical XRM (scanning & full field):** acquire information in real space
- BUT: (1) limited in resolution and focal depth by the optical elements; (2) dynamics of non-periodic systems > ns; (3) radiation damage: serious issue.

The optics depth and spatial resolution limitations can be overcome by image reconstruction from measured coherent X ray scattering pattern visualizing the electron density of non-crystalline sample:.

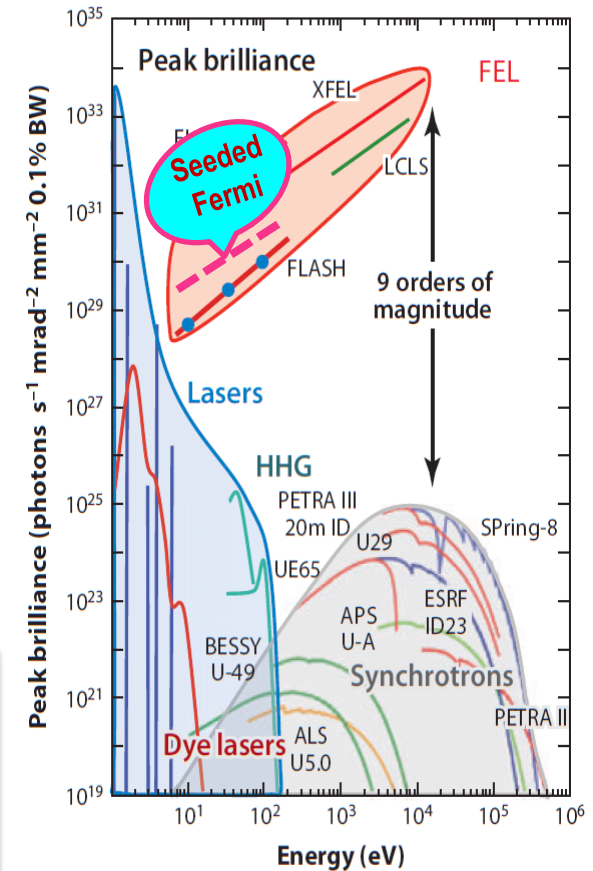


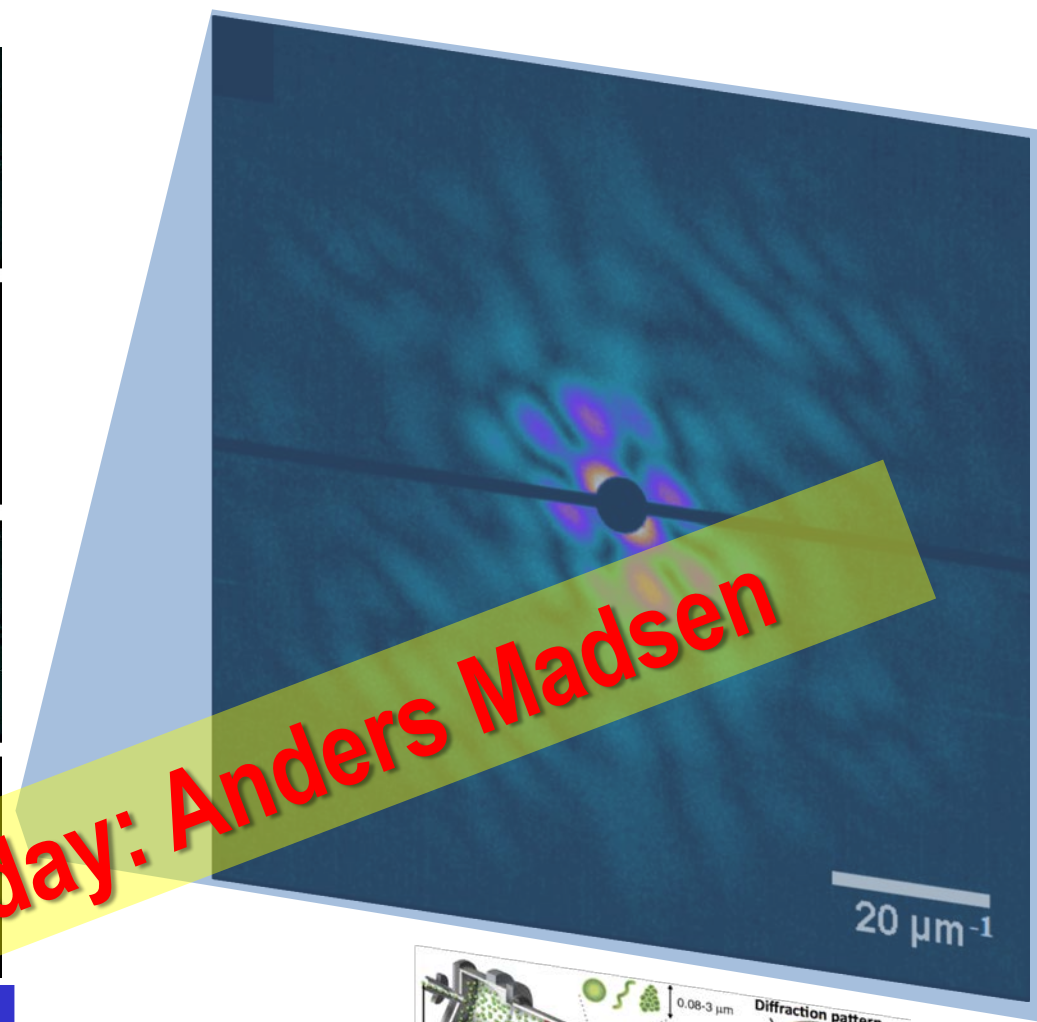
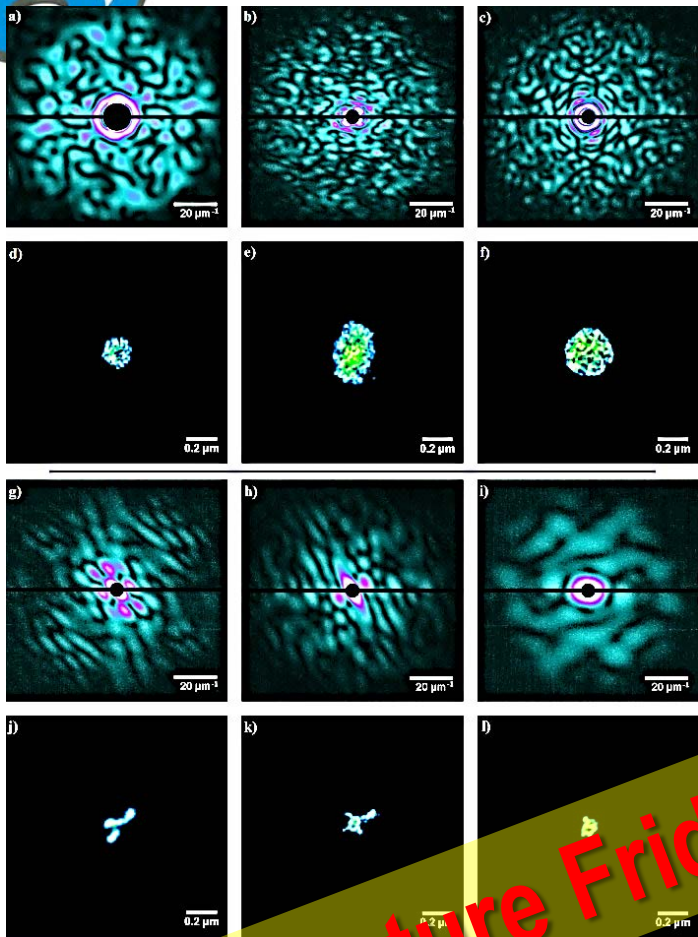
CDI acquire data in reciprocal space:
Resolution: $\delta = \lambda / \sin\theta$

computationally demanding phase retrieval



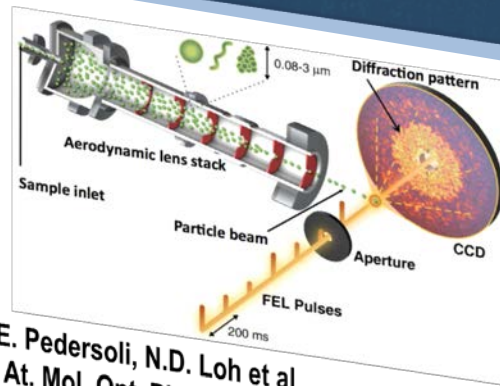
Ultra-short (fs) and ultra-bright FEL pulses allow imaging with single pulse before the radiation damage manifests itself !





Lecture Friday: Anders Madsen

Appealing to explore the new collective properties resulting from the secondary structures of the assembled NP



E. Pedersoli, N.D. Loh et al
 J. Phys. B: At. Mol. Opt. Phys., 46 (2013) 164033

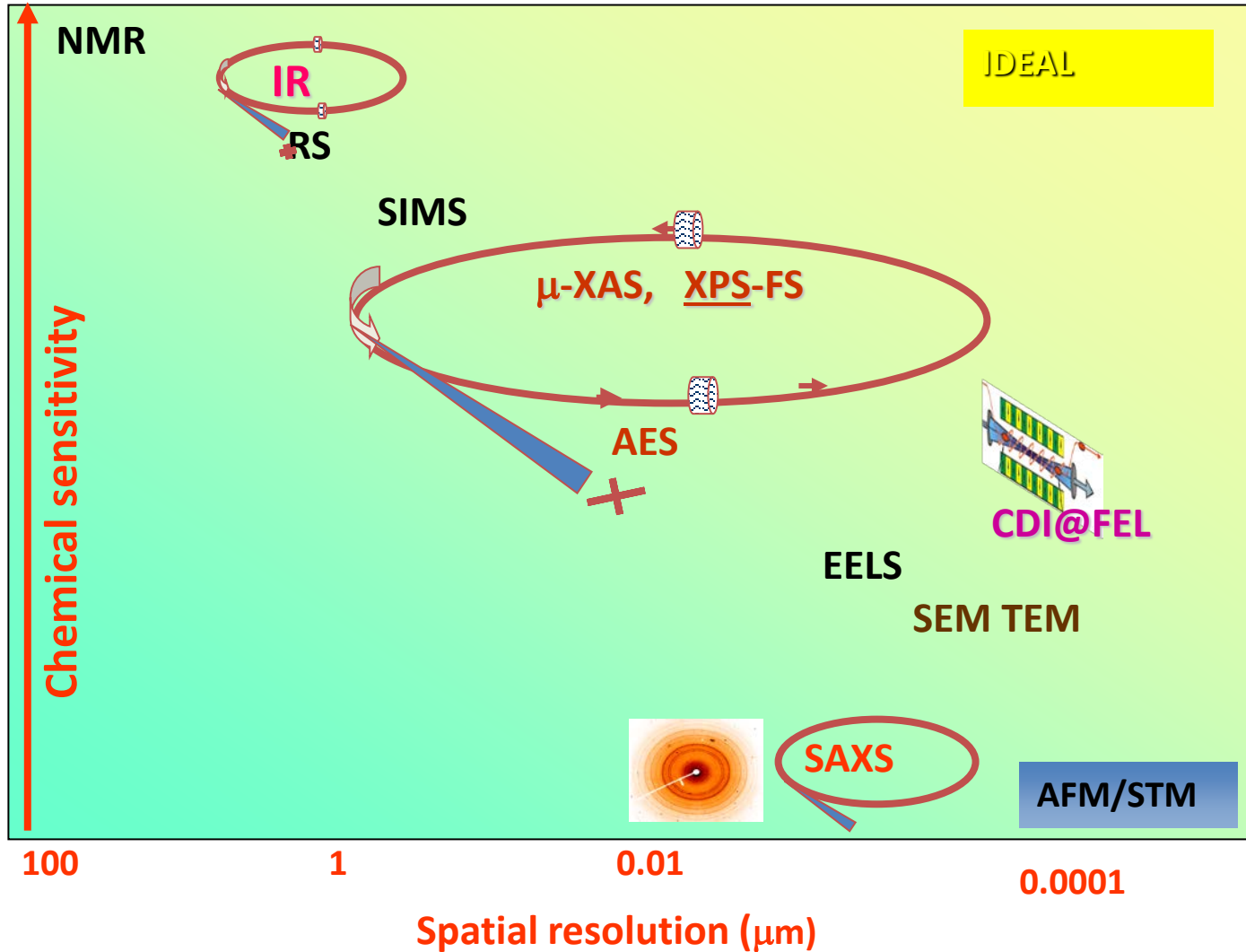
Maya Kiskinova

Duane Loh: XRM2014 - 11:40 Thursday room 203





Chemical specificity and resolution using SR

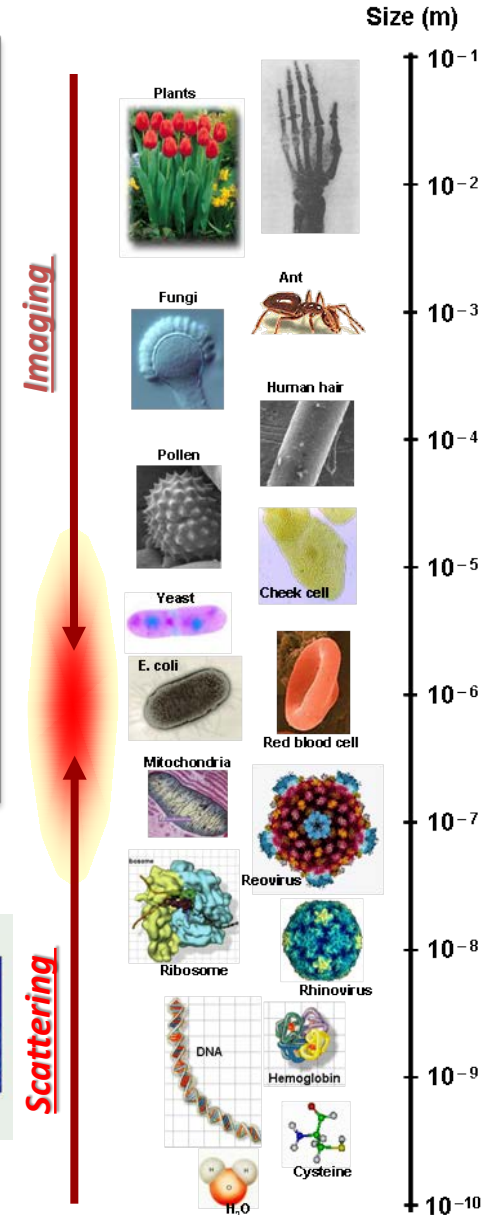
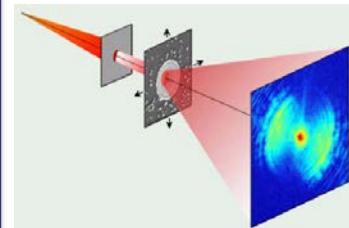




Imaging-resolution-penetration-time

- Scanning microscopes monitoring electrons - limited to surfaces.
- Transmission electron microscopes can resolve even atoms but are limited in penetration (samples thinner than ~ 30 nm).
- X-ray crystallography reveals the globally averaged 3D atomic structures based on the diffraction phenomenon, but requires crystals.
- Classical x-ray microscopy – limited in resolution and focal depth by the optical elements. Temporal resolution - \geq ns

The optics depth and resolution limitations can be overcome by image reconstruction from measured coherent X ray scattering pattern visualizing the electron density of non-crystalline sample.





Enjoy the following Lectures

X-ray microscopy: absorption, phase contrast, ptychography

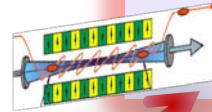
(Lecture Gianoncelli)

- 2D/3D morphology
- High resolution.
- Density mapping.

X-ray (Coherent) Scattering

(A. Madsen)

- Structure: stress/strain/texture 2D/3D mapping.
- Chemistry at resonances



Hard X-ray Imaging and tomography

(Lecture Tromba)

SXM – XRF and XAS

(Lecture: Gianoncelli)

- Elemental quantification
- Elemental mapping
- Bulk sensitive

Photoelectron imaging and Spectromicroscopy with XPEEM :

(Lecture: Locatelli)

- Chemical state
- Chemical and magnetic mapping.
- Surface sensitive.

Infrared Spectromicroscopy

(Lecture: Vaccari)

- Molecular groups and structure
- High S/N for organic matter
- Functional group imaging.
- Modest resolution but non-destructive radiation.

